WWG ANT-20SE

Advanced Network Tester “Speed Evolution” – SDH

The test solution that sets the pace in analyzing digital communications systems

- *Multi-rate transmission testing from E1 to STM-64*
- *Modular platform offering PDH, SDH, SONET and ATM capabilities*
- *Built-in Pentium PC and Windows 95 user interface for easy processing of test results*
- *Complemented by a lot of easy-access, automated test features*
- *Large, color touch-screen plus graphical results presentation*

As digital communications networks expand, the number of network operators is growing too, and not just due to providers merging across boarders. Different networks such as GSM, CATV and Internet are converging too. Nowadays, customers demand next-to-perfect network availability, and a top-level transmission quality has become a given.

ANT-20SE: A design future-proofed for success

Powerful, precise test capability or simple operation? PDH, SDH, SONET with all bit rates from 1.5 Mbit/s to 10 Gbit/s, or ATM? Don’t worry about alternatives! You dont’t have to choose. ANT-20SE delivers sophisticated, precision testing that is easy to use even in the most demanding environment for all the above bit rates and for ATM. In addition comprehensive jitter/wander measurements up to STM-16 in complete compliance with the ITU-T Rec. O.172 for comparable, insightful and accurate measurement results.

The remote operation facilities, gives you the opportunity to reduce your costs e.g. operating the instrument from any windows PC via modem or Ethernet LAN. Always ready for new standards, higher bit rates and the intelligent system components of the future the ANT-20SE is at the forefront of network installation and manufacturing applications. Now with the ANT-10Gig a subset of the ANT-20SE, it is taking you one step further allowing the analysis of STM-64/OC-192 signal structures.
One outstanding feature of the ANT-20 test solution has always been its ease of use, thanks to the very large display and graphical user interface based on Windows 95. The new ANT-20SE is even better since the size and brightness of the display have been further improved. The high speed access buttons are another useful detail, allowing you to rapidly launch commonly occurring measurements.

WAVETEK
WANDEL
GOLTERMANN
Communications Test Solutions

	ANT-20SE – SDH – mainframe	BN 3060/01 ☐
SDH page 3–9	**Extended SDH testing**	BN 3060/90.01 ☐
	Add SONET	BN 3060/90.03 ☐
	Drop & Insert/Through mode	BN 3060/90.10 ☐
	Mux/Demux 140/64	BN 3060/90.11 ☐
	M13 Mux/Demux	BN 3060/90.12 ☐
Optic page 10–13	**STM-0/-1 1310 nm**	BN 3060/91.01 ☐
	STM-0/-1 1310/1550 nm	BN 3060/91.02 ☐
	STM-0/-1/-4 1310 nm	BN 3060/91.11 ☐
	STM-0/-1/-4 1310/1550 nm	BN 3060/91.12 ☐
	STM-0/-1/-4/-16 * 1310 nm + c	BN 3060/90.55 ☐
	STM-0/-1/-4/-16 * 1550 nm + c	BN 3060/90.56 ☐
	STM-0/-1/-4/-16 * 1310/1550 nm + c	BN 3060/90.57 ☐
	STM-0/-1/-4 1310 nm + STM-16 1550 nm + c	BN 3060/90.58 ☐
CONC page 11–13	**STM-4c BERT**	BN 3060/90.90 ☐
	STM-4c ATM	BN 3060/90.91 ☐
	STM-4c virtual	BN 3060/90.92 ☐
	STM-16c BERT	BN 3060/90.93 ☐
Jitter page 14–19	**Jitter/Wander up to 155 Mbit/s**	BN 3060/91.30 ☐
	Jitter/Wander up to 622 Mbit/s	BN 3060/91.31 ☐
	Jitter/Wander up to 2.5 Gbit/s	BN 3060/91.32 ☐
ATM page 20–25	**ATM Basic**	BN 3060/90.50 ☐
	ATM Comprehensive (PVC + SVC)	BN 3060/90.51 ☐
	Add ATM SDH	BN 3060/90.52 ☐
	Add ATM SONET	BN 3060/90.53 ☐
CATS page 26–27	**CATS Test Sequencer**	BN 3035/95.90 ☐
	CATS DWDM	BN 3045/93.43 ☐

* For STM-16 only see chapter optical interface

Specifications ANT-20SE – SDH version

ANT-20SE mainframe BN 3060/01

Includes:

- Generator and analyzer for electrical STM-1signals allowing:
  - Simulation and evaluation in the SOH / POH
  - Generation and analysis of Anomalies and Defects
  - Pointer generator and analyzer
- Generator and analyzer for PDH BERT at 2, 8, 34 and 140 Mbit/s with framed and unframed patters
- C12 Mapping
- Touchscreen
- CPU RAM extension to 32MB
- 4 extension slots

Generator unit

Digital outputs
Interfaces to ITU-T Recommendation G.703
75 Ω unbalanced output, adapter jack selectable from Versacon 9 adapter system
Bit rates and line codes
2048, 8448 and 34368 kbit/s . . . . . HDB3, CMI
139264 and 155520 kbit/s . . . . . CMI

120 Ω balanced output, Lemosa jack
Bit rate and line codes
2048 kbit/s . . . . . HDB3, CMI

Bit rate offset . . . . . ±500 ppm
Step size . . . . . 0.001 ppm

Clock
Internal clock generation
at all of the bit rates listed above.
Clock stability . . . . . ±2 ppm

Synchronisation to external signals
via 75 Ω unbalanced input, BNC jack:
– Reference clock . . . . . 2048 kHz and 1544 kHz
– 2048 kbit/s (HDB3), 1544 kbit/s (B8ZS) or
– Receive signal

Clock outputs
– Clock output at frequency of generator signal, approx. 400 mV (when terminated into 75 Ω), BNC jack.

2048 kHz reference clock output via trigger output

STM-1 output signal
Generation of a STM-1 signal conforming to ITU-T Recommendation G.707

Mappings
The C12 mapping is included in the basic instrument. Other mappings can be added as needed.
Content of the selected container:
– Framed or unframed PDH test pattern
– PDH multiplex signal (with 64k/140M Mux/Demux chain option)
– External PDH signal (with D&I option)
– Test pattern without stuffing bits (bulk signal to O.181)

Content of non-selected containers . . . . . framed PRBS 2^{11}–1

The various mappings are described along with the options.

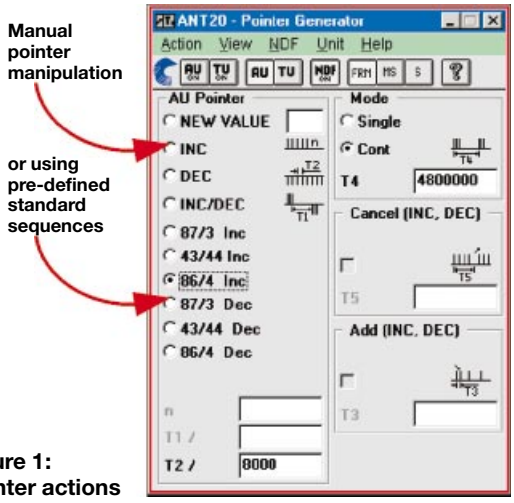


Figure 1: Pointer actions

Generation of Pointer actions (figure 1)
Generation of pointer actions at the AU and TU levels simultaneously.
– Pointer sequences to G.783 with programmable spacing
– Pointer increment/decrement (continuously repeated)
– Single pointer
– Pointer value setting with or without NDF
Trigger types: Single or continuous repeat

Contents of SDH and POH bytes
The content of all bytes with the exception of B1/B2/B3 and H1 to H4 is programmable with any byte or a user defined byte-sequence p in m in n (p frames in m frames and the entire sequence repeated n times) can be inserted.
Bytes E1, E2, F1, F2, and byte groups D1 to D3 and D4 to D12:
– Transmission of a PRBS test pattern with bit error insertion (see test patterns)
– Insertion of an external data signal via V.11 interface (also for K1, K2 and K3)

Trace identifier
J0, J1, J2 . . . programmable 16 byte ASCII sequence with CRC
J1, J2, additionally . . . . . programmable 64 byte ASCII sequence
H4 byte . . . . . 4 or 48 byte sequence

Error insertion
Error types . . . . . B1, B2, B3 parity errors frame alignment signal errors, MS-REI, HP-REI,bit errors in test pattern, code errors (single errors)

Triggering
Single error or error ratio . . . . . 2×10^{-3} to 1×10^{-10}
for B1, B3, HP-REI . . . . . 2×10^{-4} to 1×10^{-10}
for bit errors . . . . . 2×10^{-2} to 1×10^{-9}
Step size for mantissa and exponent 1

Burst error: m anomalies in n periods
For FAS, B1, B2, B3, MS-REI, HP-REI . . . . . $m = 1$ to 4.86×10^6 and n = 2 to 8001 frames or 0.2 s to 600 s

Alarm generation, dynamic
Alarm types . . . LOS, LOF, HP-PLM, MS-AIS, MS-RDI, AU-LOP, AU-AIS, HP-UNEQ, HP-RDI, HP-RDIEP, HP-RDIES, HP-RDIEC

m alarms in n frames . . . . . m = 1 to n–1, n_{max} = 8000
or
t1 alarm active,
t2 alarm passive . . . . . t1 = 0 to 60 s, t2 = 0 to 600 s

Alarm generation, static (on/off)
Alarm types ..... LOS, LOF, MS-AIS, RS-TIM, MS-RDI, AU-LOP, AU-AIS, HP-UNEQU, HP-PLM, HP-TIM, HP-RDI, HP-RDIEP, HP-RDIES, HP-RDIEC

PDH output signals

Signal structures for all bit rates:
– Unframed test pattern
– Framed test pattern (to ITU -T O.150);
CRC-4 selectable for 2 Mbit/s

Error insertion
Error types ..... bit errors, FAS errors, code errors (single errors)
Trigger types: Single error or
error rate ..... 2×10^{-3} to 1×10^{-8}
Step size for mantissa and exponent 1

Alarm generation, dynamic
Alarm types ..... LOF, RDI
m alarms in n frames ..... m = 1 to n–1, n_{max} = 1000

Alarm generation, static (on/off)
Alarm types ..... LOS, LOF, AIS, RDI

Test patterns

Pseudo-random bit sequences
PRBS: 2^{11}–1, 2^{15}–1, 2^{20}–1, 2^{23}–1, 2^{11}–1 inv., 2^{15}–1 inv., 2^{20}–1 inv., 2^{23}–1 inv.

Programmable word
Length ..... 16 bits

Receiver unit

Digital inputs
Interfaces to ITU-T Recommendation G.703
75 Ω unbalanced input; adapter jack selectable from Versacon 9 adapter system
Bit rates and line codes
2048, 8448 and 34368 kbit/s ..... HDB3, CMI
139264 and 155520 kbit/s .....CMI

120 Ω balanced input, Lemosa jack
Bit rate and line codes
2048 kbit/s ..... HDB3, CMI
Clock recovery pulling range ..... ±500 ppm

Selectable input gain
CMI coded ..... 15 to 23 dB
B3ZS, B8ZS, HDB3, AMI coded ..... 15 to 26 dB

Selectable adaptive equalizers for 1544, 2048, 34368, 44736, 51840, 139264 and 155520 kbit/s

Monitor input for STM-1 and STM-4 NRZ signals

STM-1 and PDH receive signals
Signal structures as for generator unit

Trigger output
75 Ω BNC connector, HCMOS signal level
Pulse output for received bit errors, transmit frame trigger, transmit pattern trigger or 2048 kHz reference clock

Included mapping

C12 mapping
(2 Mbit/s in STM-1, AU-3/AU-4)
Modes ..... asynchronous, byte synchronous (floating)
Error insertion and measurement
Additional error types ..... BIP2, B3 parity errors, LP-REI, LP-BIP

Alarm generation, dynamic
Alarm types ..... TU-LOP, TU-AIS, LP-PLM, TU-LOM, LP-UNEQ, LP-RDI, LP-RDIEP, LP-RDIES, LP-RDIEC, LP-RFI
m alarms in n frames ..... m = 1 to n–1, n_{max} = 8000
or
t1 alarm active,
t2 alarm passive ..... t1 = 0 to 60 s, t2 = 0 to 600 s

Alarm generation, static (on/off) and evaluation
Alarm types .....TU-LOP, TU-AIS, TU-LOM, LP-UNEQ, LP-PLM, LP-TIM, LP-RDI, LP-RDIEP, LP-RDIES, LP-RDIEC, LP-RFI
Alarm detection only ..... TU-NDF

Automatic modes

Autoconfiguration
Automatically sets the ANT-20SE to the input signal.
The routine searches at the electrical and optical interfaces for the presence of standard PDH and STM-N signals (G.703, G.707, O.151, O.181) and the payload contents in channel 1.

Automatic SCAN function
The SCAN function permits sequential testing of all C11 or C12 channels via AU-3 or AU-4 in a SDH signal.
The ANT-20SE receiver checks for alarms in the receive signal, the SDH structure and all channels, and for synchronization of the selected test pattern in all channels. The results (OK / not OK) for each channel are entered in a matrix.
The generator runs simultaneously and can be used to stimulate the device under test.

Automatic TROUBLE SCAN function (figure 2)
The TROUBLE SCAN function permits sequential testing of all C11 or C12 channels via AU-3 or AU-4 in a SDH signal.
The ANT-20SE receiver checks for alarms in the receive signal, the SDH structure and all channels. The results (OK / not OK) for each channel are entered in a matrix.
A detailed alarm history can be displayed by selecting a channel from the matrix.
The alarm status of individual channels can be displayed following the measurement.
Only the receive channels are altered during a TROUBLE SCAN.

AutoScan function (figure 3)
This automatic “AutoScan” function allows you to rapidly check the signal structure, the mapping used, the trace identifier and the payload – even with mixed mapped signals.
The ANT-20SE receiver analyzes the incoming received signal and provides a clear overview of all the signals present in the composite receive signal. The variable scan depth setting allows even complex signal structures to be resolved and displayed clearly. All the displayed results can be printed out. Delay time 1 to 10 s.

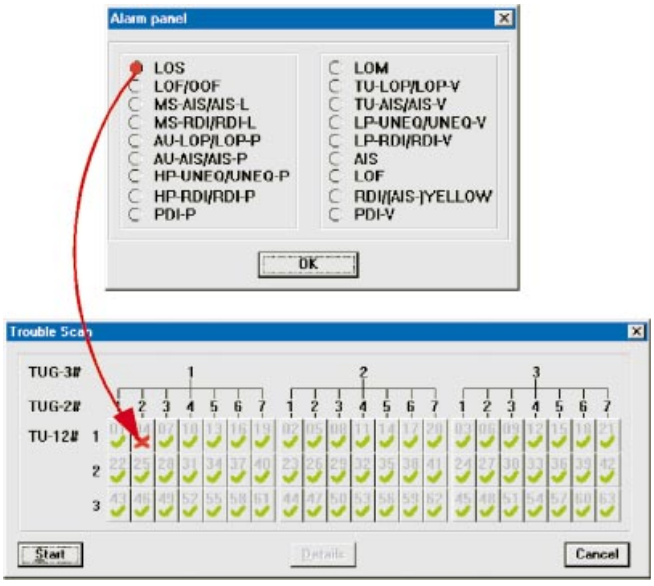


Figure 2: Trouble scan

Automatic SEARCH function
Channel shifts in the payload may occur when measuring complex network elements, depending on the configuration of the device under test. The SEARCH function permits rapid automatic location of the test channel (C11 or C12 with defined PRBS) in the payload of a SDH signal.
The ANT-20SE receiver checks for alarms in the receive signal, the SDH structure and all channels, and for synchronization of the selected test pattern in all channels. The results (OK / not OK) for each channel are entered in a matrix.
An OK result indicates that the corresponding channel contains the signal searched for. Only the receive channels are altered during a SEARCH.

Measurement types

Error measurements
Error types . . . . . B1, B2, B3 parity errors
MS-REI, HP-REI, bit errors in test pattern, code errors

Analysis of AU and TU pointer actions (figure 4)
Display of
– Number of pointer operations:
Increment, Decrement, Sum (Increment + Decrement), Difference (Increment – Decrement)
– Pointer value

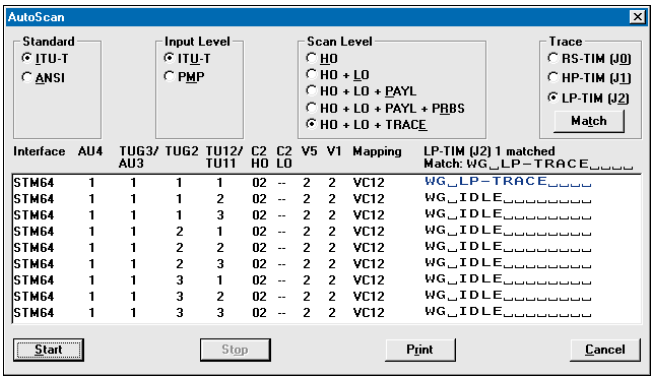


Figure 3: AutoScan

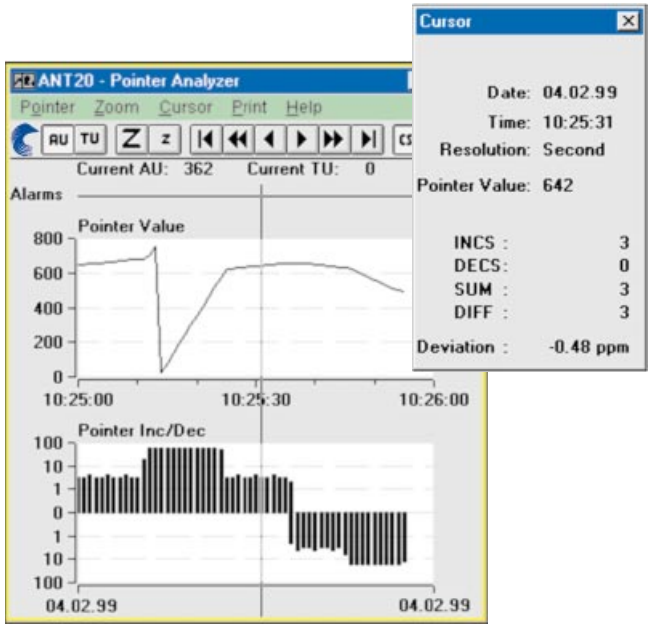


Figure 4: Graphic pointers. Display showing additional evaluation of cursor position

Clock frequency measurement
The deviation of the input signal clock frequency from the nominal frequency is displayed in ppm.

Alarm detection
All alarms are evaluated and displayed in parallel
Alarm types . . . . . LOS, OOF, LOF, MS-AIS, MS-RDI, RS-TIM, LTI, AU-AIS, AU-LOP, AU-NDF, HP-RDI, HP-UNEQ, HP-TIM, HP-PLM, AIS, RDI, LSS

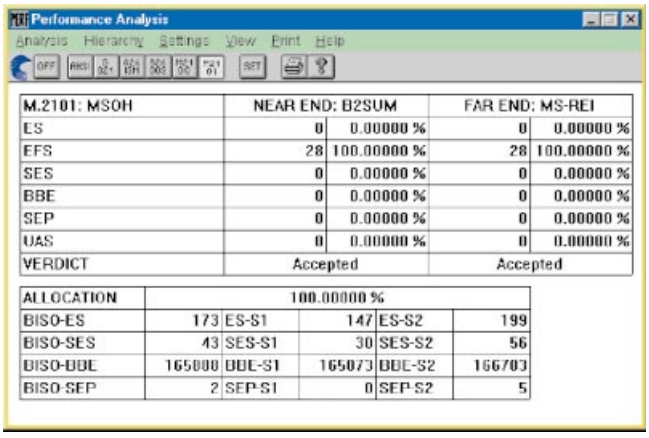
SOH and POH evaluation
– Display of complete SOH and POH, e.g. interpretation of APS information in K1 and K2

For the bytes E1, E2, F1, F2 and byte groups D1 to D3 and D4 to D12:
– BERT using test pattern from the generator unit
– Output of the data signal via the V.11 interface (also for K1, K2, K3, N1 and N2)

For the Trace Identifier
– J0 . . . . . display of 16 byte ASCII sequence
– J1, J2 . . . . . display of 16 or 64 byte ASCII sequence

Measurement interval
Variable . . . . . 1 second to 99 days
Measurement start . . . . . manual or automatic timer (user setting)
Measurement stop . . . . . manual or automatic timer (user setting)

Memory for errors, pointer operations and alarms
Resolution of error events and pointers . . . . . 1 s
Alarm resolution . . . . . 100 ms
Memory capacity . . . . . up to 1 million entries (approx. 100 days at 7 entries per minute)



M.2101: MSOH	NEAR END: B2SUM		FAR END: MS-REI	
ES	0	0.00000 %	0	0.00000 %
EFS	28	100.00000 %	28	100.00000 %
SES	0	0.00000 %	0	0.00000 %
BBE	0	0.00000 %	0	0.00000 %
SEP	0	0.00000 %	0	0.00000 %
UAS	0	0.00000 %	0	0.00000 %
VERDICT	Accepted		Accepted	

ALLOCATION	100.00000 %				
BISO-ES	173	ES-S1	147	ES-S2	199
BISO-SES	43	SES-S1	30	SES-S2	56
BISO-BBE	165000	BBE-S1	165073	BBE-S2	166703
BISO-SEP	2	SEP-S1	0	SEP-S2	5

Figure 5: Perforamnce analysis to ITU-T M.2101

Evaluation of PDH and SDH systems to ITU-T Recommendation G.821
ES, EFS, SES, DM and UAS are evaluated.
Pass / fail assessment based on line length allocation of 0.1 to 100%.
The SES and DM thresholds are user-settable.
Evaluation for higher bit rates (up to 140 Mbit/s) is obtained using a multiplex factor as per G.821, Annex D.

Measurements can be made using the following events:
PDH systems . . . . . bit errors, FAS2, FAS8, FAS34 FAS140, CRC and E bit errors
SDH systems . . . . . payload bit errors (PDH and bulk), overhead bytes E1, E2, F2, D1 to D3, D4 to D12

Evaluation to ITU-T Recommendation G.826
EB, BBE, ES, EFS, SES and UAS are evaluated.
Pass / fail assessment based on line length allocation of 0.1 to 100%.
The SES and UAS thresholds are user-settable.

In-service measurement (ISM)
Simultaneous in-service measurement of near end and far end of a selected path:
– Near end: B1, B2, HP-B3, LP-B3, BIP2, FAS at 140/34/8 or 2 Mbit/s, CRC-4
– Far end: HP-REI, LP-REI, E bit at 2 Mbit/s

Out of service measurement (OOS)
Out of service measurement using bit errors in the test pattern (for PDH and SDH).

Evaluation of PDH and SDH systems to ITU-T Recommendation M.2100
This recommendation describes requirements during line-up and maintenance (in-service)
ES, EFS, SES and UAS are evaluated.
Pass / fail assessment based on line length allocation of 0.1 to 100%.
The UAS and BISO (bringing into service objectives) thresholds are user-settable.
ISM simultaneously for near end and far end of a selected path:
PDH systems, near end . . . . . bit errors, FAS2, FAS8, FAS34, FAS140, CRC-4
far end . . . . . E bit at 2 Mbit/s
SDH systems . . . . . payload bit errors (PDH and bulk), overhead bytes E1, E2, F2, D1 to D3, D4 to D12

This operating mode allows application of the "Bringing into Service" procedures as per ITU-T Rec. **M.2110** and the determination of "Performance Information" as per ITU-T Rec. **M.2120.**

Evaluation of SDH systems to ITU-T Recommendation M.2101 (figure 5)
This recommendation provides limits for bringing-into-service and maintenance of interantional SDH paths and multiplex sections.
ES, EFS, SES, BBE, SEP and UAS are evaluated.
Pass / fail assessment based on line length allocation of 0.1 to 100%.
The UAS and BISO (bringing into service objectives) thresholds are user-settable.
ISM simultaneously for near end and far end of a selected path:
PDH systems, near end . . . . . B1, B2SUM, B3, BIP8, BIP2, bit errors (TSE)
far end . . . . . MS-REI, HP-REI, LP-REI

Delay measurement
A delay measurement is used to line-up satellite hops, to test the maximum permitted latency in storage exchanges and cross-connect systems and to check the loop circuits of regenerators.
The ANT-20SE measures the time taken for the test pattern to be transmitted from the generator back to the receiver via the path under test.
The measurement is made on the test patterns in the selected channel, in the containers (bulk or PDH) for SDH or in the selected channel at the lowest hierarchy level of PDH multiplex systems.
To avoid ambiguities in the measurement, two measurement times are provided.

Measurement range
Bit rates from 8 to 155 Mbit/s . . . . . 1 µs to 1 s
Bit rate 2 Mbit/s . . . . . 10 µs to 5 s
Bit rate 64 kbit/s . . . . . 100 µs to 16 s

Off-line analysis software
The software runs on standard PCs and permits comprehensive analysis of stored ANT-20SE results. After loading the results, the ANT-20SE settings during the measurement and the stored results can be accessed. Zoom and filter functions allow detailed evaluations. The processed results can be exported in CSV format for importing into other programs such as MS Excel or MS Word for Windows for producing documentation.

Results display and instrument operation

Numerical display
Display of absolute and relative values for all error types
Intermediate results . . . . . every 1 s to 99 min

Graphical display (histogram) (figure 6)
Display of errors, pointer operations / values and alarms as bargraphs vs. time
Units, time axis . . . . . seconds, minutes, 15 minutes, hours, days

Tabular display
Display of all alarm and error events with time stamp

Result printout
ANT-20SE supports a variety of dot-matrix, inkjet and laser printers (Windows Print Manager)

Specifications ANT-20SE – SDH version

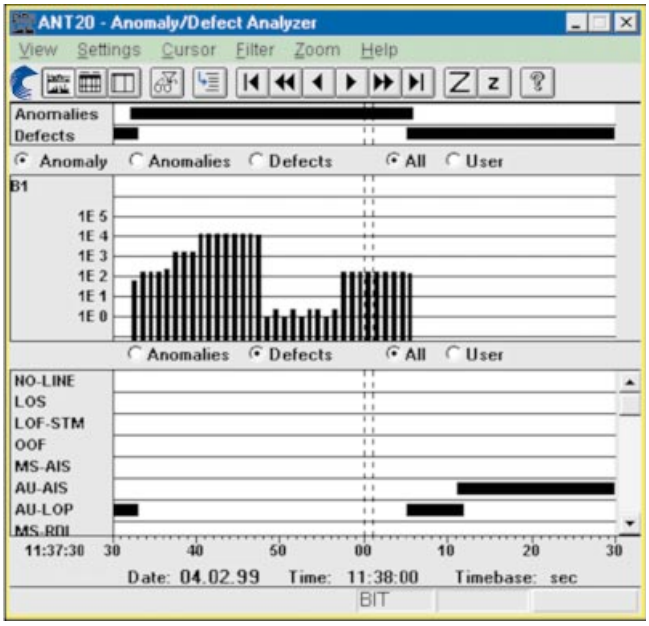


Figure 6: Histogram result display

Printer interfaces
Serial ..... V.24 / RS 232
Parallel ..... Centronics / EPP / IEEE P 1284

Result export
Results are stored in a database and can be processed using standard PC software

Instrument operation
ANT-20SE is operated using the standard Microsoft® Windows™ graphical user interface.
Operation is menu-controlled using the trackball or optional touchscreen.
A mouse can also be connected if desired.

Application selection and storage
ANT-20SE includes an applications library to which customer-specific applications can be added.
All applications are stored internally on the built-in hard disk drive and can be copied to any other ANT-20SE via floppy disk.
Easy to use filter functions allow quick selection of the desired application.

Display
A large display screen is available for the ANT-20SE:
Color TFTscreen ..... 10.4″, 256 colors
Resolution ..... 640 × 480 pixels (VGA standard)

Built-in PC
ANT-20SE uses a Pentium PC as internal controller so that standard PC applications can also be run on the instrument.
RAM capacity ..... 32 MB
Floppy drive ..... 3.5″, 1.44 MB
Hard disk drive ..... 1.4 GB (minimum)

Keyboard
Full keyboard for text input, extended PC applications and future requirements. The keyboard is protected by a fold back cover.
An additional connector is provided for a standard PC keyboard.

External display connector
Simultaneous display with built-in screen
Interface ..... VGA standard

PCMCIA interface
Type ..... PCMCIA 2.1 types I, II and III
The PCMCIA interface provides access to GPIB, LANs, etc., via adapter cards.

Power outage function
In the event of an AC line power failure during a measurement, ANT-20SE saves all data.
As soon as the AC line voltage is reestablished, the measurement is resumed. Previous results are retained and the time of the power failure is recorded along with other events.

General specifications

Power supply
AC line voltage,
automatic switching ..... 100 to 127 V and 220 to 240 V
AC line frequency ..... 50 / 60 Hz
Power consumption (all options fitted) ..... max. 230 VA
Safety class to IEC 1010-1 ..... Class I

Ambient temperature
Nominal range of use ..... +5 °C to + 40 °C
Storage and transport range ..... -20 °C to + 70 °C

Dimensions (w × h × d) in mm ..... approx. 320 × 350 × 280
in inches ... approx. 12.6 × 13.8 × 11

Weight ..... approx. 15 kg / 33 lb

Options

Extended SDH testing BN 3060/90.01

C3 mapping
(34 Mbit/s in STM-1, AU-3/AU-4)
Error insertion and measurement
Additional error types ..... LP-B3, LP-REI

Alarm generation, dynamic
Alarm types ..... TU-LOP, TU-AIS, LP-UNEQ, LP-RDI, LP-RDIEP, LP-RDIES, LP-RDIEC, LP-RFI
m alarms in n frames ..... m = 1 to n–1, n_{max} = 8000
or
t1 alarm active,
t2 alarm passive ..... t1 = 0 to 60 s, t2 = 0 to 600 s

Alarm generation, static (on/off) and evaluation
Alarm types ..... TU-LOP, TU-AIS, LP-UNEQ, LP-PLM, LP-TIM, LP-RDI, LP-RDIEP, LP-RDIES, LP-RDIEC, LP-RFI
Alarm detection only ..... TU-NDF

C4 mapping
(140 Mbit/s in STM-1 and STS-3c)
Errors and alarms as for mainframe instrument

C11 mapping
(1.5 Mbit/s in STM-1, AU-3/AU-4)
Selectable via TU-11 or TU-12
Errors and alarms as for C12 mapping
(2 Mbit/s in STM-1)

C3 mapping
(45 Mbit/s in STM-1, AU-3/AU-4)
Errors and alarms as for C3 mapping
(34 Mbit/s in STM-1)

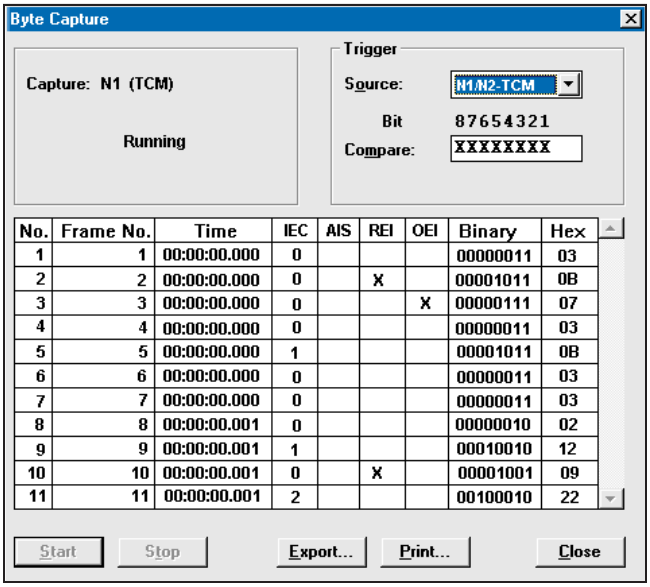
C2 mapping
(6 Mbit/s unframed/Bulk in STM-1)

Extended Overhead Analysis

Byte capture SOH and POH
To analyze the SOH/POH functions, it is necessary to capture individual bytes vs. time, allowing detection of errors or short-term changes with frame level precision.
The Capture function is started by a selectable trigger.
Values for a selected byte are stored and can be accessed subsequently in a table of values.
Particularly in capturing the **APS sequences**, the bytes (K1, K2) are displayed as an abbreviation of the standard commands.
The function also allows recording of the N1 or N2 bytes for evaluation of **"Tandem Connection"** information.
H4 sequences can also be analyzed very easily.
The results can be printed or exported.
Capture bytes for STM-0/1, el. & opt . . . . . all SOH/POH bytes
STM-N el. & opt . . . . . all SOH/POH bytes, channel 1 except A1, A2, B1
Storage depth for a byte 266
K1, K2 200
Trigger events . . . . . MS-AIS, AU-AIS, MS-RDI, AU-LOP, editable value in trigger byte
Capture resolution . . . . . frame precision

Tandem Connection Monitoring (TCM) (figure 7)
TCM is a method used to monitor the performance of a sub-section of a SDH path via the N1/N2 bytes. This is particularly useful when the path is routed via different network providers. If errors occur on an end-to-end connection, you can use TCM to determine which subnetwork the errors occurred in.
The ANT-20SE helps to monitor the content of the N1/N2 bytes and provides users with easy interpretation of the detailed events.

Figure 7: Capture with TCM trigger and interpretation



No.	Frame No.	Time	IEC	AIS	REI	OEI	Binary	Hex
1	1	00:00:00.000	0				00000011	03
2	2	00:00:00.000	0		X		00001011	0B
3	3	00:00:00.000	0			X	00000111	07
4	4	00:00:00.000	0				00000011	03
5	5	00:00:00.000	1				00001011	0B
6	6	00:00:00.000	0				00000011	03
7	7	00:00:00.000	0				00000011	03
8	8	00:00:00.001	0				00000010	02
9	9	00:00:00.001	1				00010010	12
10	10	00:00:00.001	0		X		00001001	09
11	11	00:00:00.001	2				00100010	22

Capture TCM frames . . . . . all N1/N2 bytes, TC-IEC, TC-AIS, TC-REI, TC-OEI

Trigger events . . . . . Start of TCM frame (TCM FAS word)
Storage depth . . . . . 266 bytes (3.5 TCM frames)

On-line monitoring of alarms and trace identifier.
Display of actual and history values . . . . . TC-UNEQ, LTC, TC-AIS , TC-RDI, TC-ODI, TC-REI, TC-OEI

On-line display of TCM Access Point Identifier

TCM error measurement
Error types . . . . . TC-IEC, TC-DIFF, TC-REI, TC-OEI

Overhead Sequencer
This serves to test a sequential TCM process (Tandem Connection Monitoring) in the N1/N2 bytes. A sequence of 76 bytes simulating a TCM frame (equivalent frame) is generated. Individual values can be edited as binary or hexa-decimal values to simulate various events for TCM evaluations.

APS time measurement
In synchronous networks, a defined maximum switch-over time is necessary for the traffic in case of a fault.
To verify compliance with this requirement, the ANT-20SE measures the switch-over time with 1 ms resolution.
The result can be printed.

Criteria for the time measurement . . . . . TU-AIS, MS-AIS, AU-AIS, bit error

Max. measurable switch-over time . . . . . 2 s
Resolution . . . . . 1 ms
Allowable error rate for user signal . . . . . $< 2 \times 10^{-4}$

Add SONET BN 3060/90.02

STM-0 and VT2 SPE mapping
(2 Mbit/s in STM-0 and E1 in STS-1)
See ANT-20SE SONET datasheet for details

STM-0 and VT1.5 SPE mapping
(1.5 Mbit/s in STM-0 and DS1 in STS-1)
See ANT-20SE SONET datasheet for details

Mapping VT6 SPE
(6 Mbit/s in STS-1)
See ANT-20SE SONET datasheet for details

STM-0 and STS-1 SPE mapping
(34/45 Mbit/s in STM-0 and DS3 in STS-1)
See ANT-20SE SONET datasheet for details

BERT (1.5/6/45 Mbit/s)
Signal structure and interfaces for generator and receiver:
Framed and unframed test patterns (6 Mbit/s unframed)

Additional test pattern . . . . . QRSS 20

Additionally, for unbalanced digital signal input/output
Bit rate, line code . . . . . 1544 kbit/s, 6312 kbit/s, B8ZS, AMI
Bit rate, line code . . . . . 44736 kbit/s, B3ZS

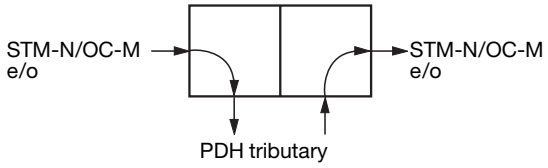
Additionally, for balanced digital signal input/output
Bit rate, code . . . . . 1544 kbit/s, B8ZS

Specifications ANT-20SE – SDH version

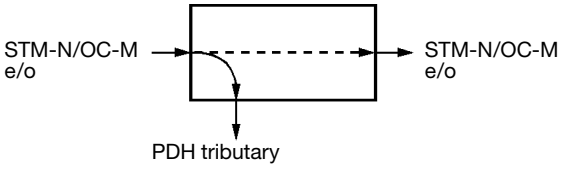
Drop & Insert BN 3060/90.10

This option provides the following functions:

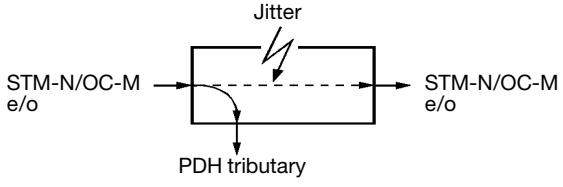
1. Generator and receiver operate independently
as mapper and demapper. The PDH signal from a selected channel is dropped from the receive signal and output to a connector. An external or internal PDH signal is inserted into the transmit signal.



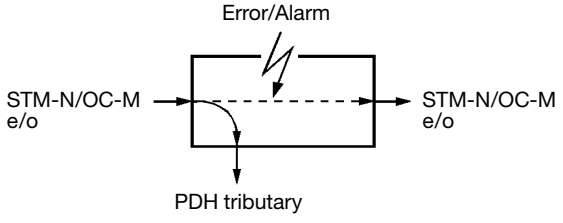
2. Through mode:
The received signal is looped through the ANT-20SE and re-transmitted (generator and receiver coupled). The PDH signal from a selected channel may be dropped from the receive signal and output to a connector. An internal PDH signal may be inserted into the transmit signal. The ANT-20SE can operate here as an active signal monitor without affecting the signal.



3. Through mode jittering:
The looped-through PDH or SDH signal can also be jittered using the Jitter Generator option. This applies to all jitter frequencies up to 622 Mbit/s depending on the jitter option fitted.



4. Error insertion in through mode:
The looped-through synchronous signal can be manipulated if required:
- Overwriting bytes in the SOH (except B1, B2, H1 to H3)
- Anomaly insertion
- Defect generation by programming the SOH



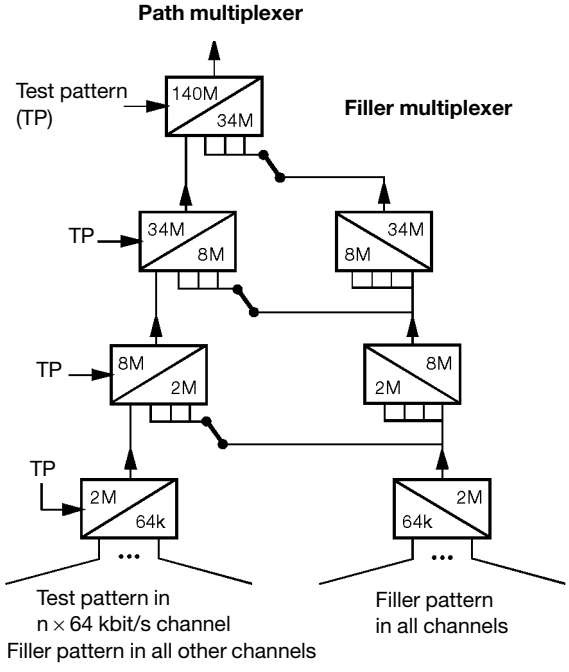
5. Block and Replace (B & R)
For this function, the ANT-20SE is looped into the working fiber of a ring. B&R allows replacement of a synchronous tributary (e.g. STM-1 including SOH, POH and payload) in a STM-N signal. This can then be measured by the ANT-20SE from the ring. By inserting specific errors, the error thresholds of the APS mechanism in the system can be tested.

Additional input and output for tributary signals
75 Ω, coaxial BNC; line codes as for mainframe instrument

Input and output for balanced tributary signals: Use balanced connectors on mainframe

64k/140M MUX/DEMUX chain BN 3060/90.11

This option provides n × 64 kbit/s to 140 Mbit/s multiplex and demultiplex functions. The output signal is fed to the electrical interface and is available as payload in mappings.
For STM-0 mappings please select the option “Add SONET”.
Alarms and errors can be generated and analyzed.



Output signal structure. Framed and unframed pseudo-random bit sequences are available as test patterns (TP) from 2 to 140 Mbit/s.

M13 MUX/DEMUX chain BN 3060/90.12

M13 multiplexers are used in North America in hybrid networks and synchronous system cross-connects. This option provides n × DS0 to DS3 multiplex and demultiplex functions. The output signal is fed to the electrical interface and is available as payload in mappings (requires option “Add SONET”).
Alarms and errors can be generated and analyzed.

Optical interfaces

All of the optical interfaces are intended for single-mode fibers. Wavetek Wandel Goltermann offers a complete line of optical test adapters. Select one test adapter each for the generator and receiver from the ordering information in this data sheet. All optical interface options include the required number of test adapters. The STM-0 optical interface requires the option "Add SONET".

Optical Modules up to 155 Mbit/s

Optical STM-0/1, OC-1/3, 1310 nm **BN 3060/91.01**

Optical STM-0/1, OC-1/3, 1310 & 1550 nm **BN 3060/91.02**

Bit rate of TX and RX signal . . . . . 155520 kbit/s
additionally, for STS-1/STM-0 mappings . . . . . 51840 kbit/s
Line code . . . . . scrambled NRZ

Generator unit
The generator meets the requirements of ITU-T Rec. G.957, Tables 2 and 3 (Bellcore GR 253, ANSI T1.105.06). Classes L1.1, L1.2 and L1.3 (LR-1, LR-2, LR-3) are covered.

There are three options for adapting to the required wavelength:
Wavelength . . . . . 1310 nm, 1310 & 1550 nm (switchable in the instrument)

Output level . . . . . 0 dBm +2/–3 dB
with 1310 & 1550 nm option . . . . . 0 dBm +2/–3.5 dB

Receiver unit
The receiver unit meets the specifications of ITU-T Rec. G.957 (Bellcore GR 253, ANSI T1.105.06) and fulfills classes S1.1 and S1.2 (IR-1, IR-2).

Wavelength range . . . . . 1100 to 1580 nm
Input sensitivity . . . . . –8 to –28 dBm (–8 to –34 dBm typ.)
Display of optical input level
Resolution . . . . . 1 dB

155 Mbit/s electrical interface
for connecting the ANT-20SE to STM-1/STS-3 monitor points
Line code . . . . . scrambled NRZ
Input voltage (peak-peak) . . . . . 0.2 to 1 V
Unbalanced input
Connector / impedance . . . . . SMA / 50 Ω

Optical Modules up to 622 Mbit/s

Optical STM-0/1/4, OC-1/3/12, 1310 nm **BN 3060/91.11**

Optical STM-0/1/4, OC-1/3/12, 1310 & 1550 nm **BN 3060/91.12**

Bit rate of TX and RX signal . . . . . 155520 kbit/s, 622080 kbit/s
additionally, for STS-1/STM-0 mappings . . . . . 51840 kbit/s
Line code . . . . . scrambled NRZ

Generator unit
The generator meets the requirements of ITU-T Rec. G.957, Tables 2 and 3 (Bellcore GR 253, ANSI T1.105.06). Classes L1.1, L1.2, L1.3, L4.1, L4.2 and L4.3 (LR-1, LR-2, LR-3) are covered.

There are three options for adapting to the required wavelength:
Wavelength . . . . . 1310 nm, 1310 & 1550 nm (switchable in the instrument)

Output level . . . . . 0 dBm +2/–3 dB
with 1310 & 1550 nm option . . . . . 0 dBm +2/–3.5 dB

Generation of STM-4 TX signal
in instruments with STM-1 mappings

The STM-4 TX signal consists of
– four identical STM-1 tributary signals (AU-4), or
– one internally generated STM-1 tributary signal with the other three tributaries filled with UNEQ.

Generation of OC-12 TX signal
in instruments with STS-1 mappings

The OC-12 TX signal consists of
– one internally generated STS-1 tributary signal with the other 11 tributaries filled with UNEQ or
– one internally generated STS-3c tributary signal with the other three tributaries filled with UNEQ.

with STS-3c mapping option or ATM Basic Option BN 3060/90.50

Contents of the STM-4/OC-12 overhead bytes
For all bytes except B1, B2 and H1 to H3:
– the content of each byte is statically programmable or a user defined byte-sequence p in m in n (p frames in m frames and the entire sequence repeated n times) can be inserted.

For the E1, E2, F1 bytes and the DCC channels D1 to D3 and D4 to D12:
– Transmission of a test pattern with bit error insertion (see mainframe for pattern selection)
– Insertion of an external data signal (via the V.11 interface)

For the K1, K2, N1, N2 bytes:
– Insertion of the data signal via the V.11 interface

For the J0 bytes:
– Transmission of a 16-byte sequence, with CRC

Error insertion
Error types . . . . . B1 and B2 parity error
additionally, for STM-4 . . . . . MS-REI
for OC-12 . . . . . REI-L

Triggering
Single errors or error ratio . . . . . 2×10^{-3} to 1×10^{-10}
for B1 parity errors . . . . . 2×10^{-4} to 1×10^{-10}

Burst error: m anomalies in n periods
For FAS, B1, B2, B3, REI-L, REI-P . . . . m = 1 to 4.8×106 and n = 2 to 8001 frames or 0.2 s to 600 s

Alarm generation, dynamic
Alarm types for STM-4 . . . . . LOF, MS-AIS, MS-RDI
for OC-12 . . . . . LOF, AIS-L, RDI-L
m alarms in n frames . . . . . m = 1 to n-1, n_{max} = 8000
or
t1 alarm active, t2 alarm passive . . . . . t1 = 0 to 60 s, t2 = 0 to 600 s

Alarm generation, static (on/off)
Alarm types . . . . . LOS, LOF
additionally, for STM-4 . . . . . MS-AIS, MS-RDI, RS-TIM
for OC-12 . . . . . AIS-L, RDI-L, TIM-L
Insertion on/off

Specifications ANT-20SE – SDH version

Receiver unit
The receiver unit meets the specifications of ITU-T Rec. G.957 (Bellcore GR 253, ANSI T1.105.06) and fulfills classes S1.1, S1.2, S4.1, S4.2, L4.1, L4.2 and L4.3 (IR-1, IR-2, LR-1, LR-2, LR-3).

Wavelength range ..... 1100 to 1580 nm
Input sensitivity, STM-1/-4, OC-1/3/12..... –8 to –28 dBm
(–8 to –34 dBm typ.)
Display of optical input level
Resolution ..... 1 dB

The ANT-20SE demultiplexes one selectable STM-1 or STS-3c/STS-1 tributary from the STM-4 or OC-12/OC-3 RX signal and feeds it to the internal processor for evaluation.

Measurement types
Error measurements
Error types ..... B1 parity error,
B2 parity error of all STM-1/STS-1/STS-3c signals,
MS-REI/REI-L
Alarm detection
Alarm types ..... LOS, LOF, OOF, LTI
additionally, for STM-4 ..... MS-AIS, MS-RDI, RS-TIM
for OC-12 ..... AIS-L, RDI-L, TIM-L

Overhead evaluation
– Display of the complete overhead of a selectable STM-1/STS-1/STS-3c signal

For the E1, E2, F1 bytes and the DCC channels D1 to D3 and D4 to D12:
– BERT using a test pattern from the generator unit
– Output of the data signal via the V.11 interface

For the K1, K2, N1, N2 bytes:
– Data signal output via the V.11 interface

For the J0 byte:
– Display of 15-byte sequences in ASCII.

155/622 Mbit/s electrical interface
For connecting the ANT-20SE to STM-1/OC-3 and STM-4/OC-12 monitor points

Line code ..... scrambled NRZ
Input voltage (peak-peak) ..... 0.2 to 1 V
Coaxial input
Connector / impedance ..... SMA / 50 Ω

Concatenated Mappings 622 Mbit/s

Option OC-12c/STM-4c BERT **BN 3060/90.90**
Only in conjunction with BN 3060/91.11 or BN 3060/91.12

Contiguous concatenation signal structure to ANSI T1.105.02 and G.707.
Error measurement to O.150
Test pattern PRBS-31, IPRBS-31
PRBS-23, IPRBS-23
PRBS-20,
PRBS-15, IPRBS-15

Programmable word
Length..... 16 bits

Error insertion
Bit errors in test pattern, single error or
error ratio ..... 1×10^{-2} to 1×10^{-9}

Error measurement and alarm detection
Bit errors and AIS in test pattern

Option OC-12c/STM-4c
Virtual Concatenation **BN 3060/90.92**
Only in conjunction with BN 3060/90.90 or BN 3060/90.91

Signal structure
STM-4 to ITU-T G.707
Virtual concatenation with 4 AU-4 pointers

Generation of pointer actions
Manipulations on pointer #1 as in basic data sheet
Setting of delta values for pointers #2, #3, #4

Pointer analysis
For pointer #1 ..... as in basic data sheet
Delta values (maximum, minimum) ..... ±40
for pointers #2, #3, #4

POH generation/analysis
POH #1 ..... as in basic data sheet
POH #2, #3, #4..... static setting of all bytes except B3

Automatic B3 generation for VC-4 #1, #2, #3, #4

Option OC-12c/STM-4c ATM-Testing **BN 3060/90.91**
Only in conjuction with BN 3060/90.50 and BN 3060/91.11 or BN 3060/91.12

See chapter “ATM options” for further details.

Optical Modules up to 2488 Mbit/s

All optical packages include OC-12c/STM-4c BULK (BN 3060/90.90), OC-48c/STM-16c BULK (BN 3060/90.93) and 4 optical adapters.

Optical OC-1/-3/-12/-48,
STM-0/-1/-4/-16, 1310 nm **BN 3060/90.55**

Optical OC-1/-3/-12/-48,
STM-0/-1/-4/-16, 1550 nm **BN 3060/90.56**

Optical OC-1/-3/-12/-48,
STM-0/-1/-4/-16, 1310 & 1550 nm **BN 3060/90.57**

Optical OC-1/-3/-12, 1310 nm,
OC-48 1550 nm
STM-0/-1/-4, 1310 nm
STM-16, 1550 nm **BN 3060/90.58**

Optical Modules 2488 Mbit/s

Optical STM-16, OC-48, 1310 nm **BN 3060/91.51**

Optical STM-16, OC-48, 1550 nm **BN 3060/91.50**

Optical STM-16, OC-48,
1310/1550 nm switchable **BN 3060/91.52**

One 2.5 Gbit/s module can be fitted in the extension slot of the ANT-20SE.

The optical interfaces meet the specifications of ITU-T Recommendation G.957 (Table 4) and Bellcore TA-NWT-000253 I.6 (Table 4–9, 4–10).
Classes S-16.2, L-16.2, L-16.3 (ITU-T) or IR-2, LR-2, LR-3 (Bellcore) are fulfilled at 1550 nm; classes S-16.1, L-16.1 (G.957) or IR-1, LR-1 (Bellcore) are fulfilled at 1310 nm.

Generator

Optical interfaces
Wavelengths ..... 1310 nm, 1550 nm or 1310/1550 nm switchable
Output level at 1310 nm and 1550 nm ..... 0 dBm +0/–2 dB
Line code ..... scrambled NRZ

Electrical interfaces
Line code ..... scrambled NRZ
Output voltage (peak-peak) ..... ≥ 0.6 V
Connector / impedance ..... SMA / 50 Ω

Clock generator
Internal, accuracy ..... ±2 ppm
Offset ..... ±50 ppm
Synchronization from external signal as for mainframe

Generation of STM-16 TX signal
in instruments with STM-1 mappings

The STM-16 signal consists of one or more internally generated tributaries plus several tributaries filled with UNEQ (or non-specific UNEQ)
– 16 identical STM-1
– one STM-1 tributary and 15 × UNEQ/non specific
– 4 identical STM-4c (Option BN 3060/90.90 required)
– one STM-4c tributary (Option BN 3060/90.90 required) and 3 × UNEQ/non specific

Generation of OC-48 TX signals
in instruments with STS-1/STS-3c mappings

The OC-48 signal consists of one or more internally generated tributaries plus several tributaries filled with UNEQ (or non-specific UNEQ)
– 48 identical STS-1
– one STS-1 tributary and 47 × UNEQ/non specific
– 16 identical STS-3c (Option BN 3060/90.02 required)
– one STS-3c tributary (Option BN 3060/90.02 required) and 15 × UNEQ/non specific
– 4 identical STS-12c (Option BN 3060/90.90 required)
– one STS-12c tributary (Option BN 3060/90.90 required) and 3 × UNEQ/non specific

Contents of STM-16/OC-48 overhead bytes
For all bytes except B1, B2 and H1 through to H3:
– the contents of the bytes in all SOH/TOH are statically programmable

For the bytes E1, E2, F1 and the DCC channels D1 to D3 and D4 to D12:
– Transmission of a test pattern and bit error insertion (see mainframe for pattern selection)
– Insertion of an externally-generated data signal (via V.11 interface)

For the K1, K2, N1, N2 bytes:
– Insertion of an external data signal via the V.11 interface

For the J0 byte:
– Transmission of a 16-bit sequence with CRC

Error insertion
Error types ..... B1, B2 parity errors
Single error or error rate B1 ..... 1E-10 to 2E-5
B2 ..... 1E-10 to 2E-3
additionally, for STM-16 ..... MS-REI
for OC-48 ..... REI-L
Single error or error rate ..... 1E-10 to 2E-3

Alarm generation, dynamic
Alarm types for STM-16 .....LOF, MS-AIS, MS-RDI
for OC-48 ..... LOF, AIS-L, RDI-L
m alarms in n frames ..... m = 1 to n-1, n_{max} = 8000
or
t1 alarm active, t2 alarm passive .....t1 = 0 to 60 s, t2 = 0 to 600 s

Alarm generation, static (on/off)
Alarm types ..... LOS, LOF
additionally, for STM-16 ..... MS-AIS, MS-RDI
for OC-48 ..... AIS-L, RDI-L

Receiver

Optical interfaces
Wavelength .....1260 to 1580 nm
Line code ..... scrambled NRZ
Sensitivity ..... –28 dBm to –8 dBm
Input overload ..... >–8 dBm

Display of optical input level
Range ..... –30 dBm to –8 dBm
Resolution ..... 1 dB

Electrical interfaces
Line code ..... scrambled NRZ
Input voltage (peak-peak) ..... 0.3 to 1 V
Connector / impedance ..... SMA / 50 Ω

A selectable STM-1, STS-1 or STS-3c channel is fed to the internal evaluation circuits by demultiplexing from the input signal.

Error measurement
Error types ..... B1 parity error, MS-REI, B2 parity sum error over all STM-1/STS-1/STS-3c channels
Evaluation (bit/block errors) ..... error rate, count
Error event resolution..... 1 s

Alarm detection
Alarm typs ..... LOS, LOF, OOF
additionally, for STM-16 ..... MS-AIS, MS-RDI, RS-TIM
for OC-48 ..... AIS-L, RDI-L, TIM-L
Alarm event resolution..... 100 ms

SOH/TOH evaluation
Display of complete overhead

For the bytes E1, E2, F1 and the DCC channels D1 to D3 and D4 to D12:
– BERT using test pattern from generator unit
– Output of the data signal via the V.11 interface

For the K1, K2, N1, N2 bytes:
– Data signal output via the V.11 interface

For the J0 byte:
– Display of 15-byte sequences in ASCII format

Concatenated Mapping 2488 Mbit/s

Option OC-48c/STM-16c BERT **BN 3060/90.93**
Only in conjunction with BN 3060/91.50 to /91.53

Contiguous concatenation signal structure to ANSI T1.105.02 and G.707.

Error measurement to O.150
Test pattern PRBS-31, IPRBS-31
PRBS-23, IPRBS-23

Programmable word
Length..... 16 bits

Error insertion
Bit errors in test pattern, single error or error ratio ..... 1×10^{-3} to 1×10^{-9}

Specifications ANT-20SE – SDH version

Alarm generation:
AU-AIS, AIS-C1...AIS-C16,
AU-LOP, LOP-C1...LOP-C16

Error measurement and alarm detection:
AU-AIS, AU-LOP
Bit errors

Automatic Protection Switching
Sensor: MS-AIS, AU-AIS

DWDM laser at 2488 Mbit/s

Optical STM-16, OC-48, 15xy nm **BN 3060/91.53**
Special DWDM laser to G.692
Lasers with precisely defined wavelengths in the 1550 nm range are used specifically for DWDM applications. The ANT-20SE can be fitted with a selected laser source conforming to ITU-T G.692 for such applications.

Solutions for 10 Gbit/s

With the new ANT-10Gig we provide a 10 Gbit/s solution which covers STM-64 as well as OC-192. The ANT-10Gig allows testing at the highest line bit rate and in all mappings below and offers optionally all testing down to n × 64 kbit/s.
For detailed information please refer to data sheet “ANT-10Gig”.

Further options

Optical power splitter (90/10 %) **BN 3060/91.05**
The optical power splitter is built into the ANT-20SE.
Three optical test adapters are required to operate it; please indicate your choice.

The optical power splitter provides an optical monitor point. The input signal is passed through to the output transparently.

Light energy forwarded . . . . . approx. 90 % (–0.45 dB)
Light energy coupled out . . . . . approx. 10 % (–10 dB)

The optical power splitter operates in the following ranges:
Wavelengths . . . . . 1260 to 1360 nm and 1500 to 1600 nm

OLA-15 Optical Attenuator (Variable) **BN 2239/01**

One application of OLA-15 is in line-up of optical links, where line interruptions are simulated for bit error testing. The device is also useful when measuring the sensitivity of optical receivers. With its wide variable attenuation range and highly accurate and reproducible attenuation settings, the OLA-15 is an ideal companion to the ANT-20SE.

Calibrated at . . . . . 1310 and 1550 nm
Attenuation range . . . . . 3 to 60 dB
Resolution . . . . . 0.05 dB

See OLA-15 data sheet for details.

Jitter and Wander options

Standards

Jitter generation and jitter/wander analysis are in accordance with:
- ITU-T G.783, G.823, G.824, G.825, O.171, O.172
- ETSI ETS 300 462-1 to -6, ETS 300 417-1-1, EN 302 084
- Bellcore GR-253, GR-499, GR-1244
- ANSI T1.101, T1.102, T1.105.03,T1.403, T1.404, T1.105.09

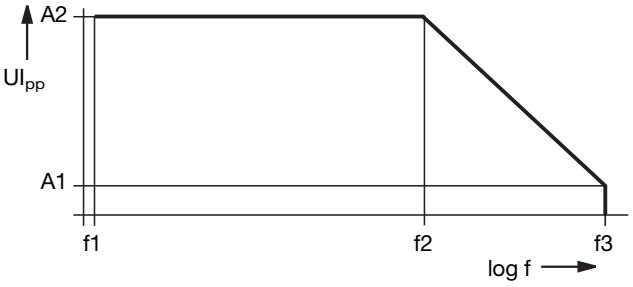
O.172 Jitter/Wander up to 155 Mbit/s — BN 3060/91.30

Jitter generator
Fully complies with or exceeds the requirements of ITU-T O.172.

Bit rates
Generates jitter at all bit rates included in the mainframe configuration up to 155520 kbit/s.

TX signals all test patterns and frame structures included in the mainframe configuration

Built-in modulation generator (sinewave) . . . . . 0.1 Hz to 5 MHz
External modulation . . . . . 0 Hz to 5 MHz
Jitter amplitude . . . . . up to 64 UI



Clock rate/kHz	A1	A2	f1 / Hz	f2 / Hz	f3 / kHz
1 544	0.5	64	0.1	625	80
2 048				1560	200
6 312				940	120
8 448				6250	800
34 368				27 k	3 500
44 736				35 k	4 500
51 840				27 k	3 500
139 264				39 k	5 000
155 520				39 k	5 000
622 080 *	1.0	256		20 k	5 000

* Requires option BN 3060/91.31

Modulator input
75 Ω, BNC socket
Voltage required . . . . . 0 to 2 Vpp

Error limits . . . . . as per O.172

Jitter Analyzer
Jitter measurement at all bit rates included in the mainframe configuration up to 155520 kbit/s.

Built-in filters
High-pass filters . . . . . 0.1, 2, 4, 10, 20, 40, 100, 200, 400, 500, 700 Hz, 1, 3, 8, 10, 12, 18, 20, 30, 65, 80, 250 kHz

Low-pass filters . . . . . 4 0, 60, 100, 400, 800, 1300, 3500, 5000 kHz
Filter characteristics . . . . . as per ITU-T O.172

Measurement ranges
Peak-peak
Range I / Resolution . . . . . 0 to 1.6 UIpp / 1 mUIpp
Range II / Resolution . . . . . 0 to 20 UIpp / 10 mUIpp
Range III / Resolution . . . . . 0 to 200 UIpp / 100 mUIpp
RMS
Range I / Resolution . . . . . 0 to 0.8 UIpp / 1 mUIpp
Range II / Resolution . . . . . 0 to 10 UIpp / 10 mUIpp
Range III / Resolution . . . . . 0 to 100 UIpp / 100 mUIpp

Measurement accuracy . . . . . as per O.172

Demodulator output
75 Ω, BNC socket
Range I (0 to 1.6 UIpp) . . . . . 1 V / UIpp
Range II (0 to 20 UIpp) . . . . . 0.1 V / UIpp
Range III (0 to 200 UIpp) . . . . . 0.01 V / UIpp

Wander Generator
Fully complies with or exceeds the requirements of ITU-T O.172

Bit rates
Wander generation at all implemented bit rates up to 155 Mbit/s according to the equipment level of the instrument.
Amplitude range . . . . . up to 200,000 UI
Frequency range . . . . . 10 µHz to 10 Hz
Accuracy . . . . . as per O.172
Resolution . . . . . 1 µHz

Wander Analyzer
Fully complies with or exceeds the requirements of ITU-T O.172

For all bit rates up to 155 Mbit/s according to the equipment level of the instrument.
Other sampling rates in addition to the 30/s rate are available for detailed analysis versus time:
Sampling rate – Low-pass filter –
Test duration . . . . . 1/s - 0.1 Hz - 99 days
30/s - 10 Hz - 99 h
60/s - 20 Hz - 99 h
300/s - 100 Hz - 5000 s
Amplitude range . . . . . ± 1 ns to $\pm 10^6$ s
Measurement accuracy . . . . . as per O.172

Accessory: “Standard Frequency Source” for wander applications, see end of chapter

O.172 Jitter/Wander up to 622 Mbit/s — BN 3060/91.31

Jitter generator
Jitter modulation of STM-4 TX signals.
Built-in modulation generator (sinewave) . . . . . 0.1 Hz to 5 MHz
External modulation . . . . . 0 Hz to 5 MHz
Jitter amplitude . . . . . up to 256 UI

Jitter modulation of externally-generated signals in Through mode
Externally-generated signals can be jittered in Through mode when the D&I option is included.

Specifications ANT-20SE – SDH version

This applies to all bit rates included in the mainframe configuration at the appropriate electrical and optical interfaces.
Built-in modulation generator (sinewave) ..... 0.1 Hz to 5 MHz
External modulation ..... 0 Hz to 5 MHz
Jitter amplitude ..... as for jitter generator in UIpp

Jitter Analyzer

Measurement range
Range I / Resolution ..... 0 to 6.4 UIpp / 1 mUIpp
Range II / Resolution ..... 0 to 80 UIpp / 10 mUIpp
Range III / Resolution ..... 0 to 800 UIpp / 100 mUIpp

RMS
Range I / Resolution ..... 0 to 3.2 UIpp / 1 mUIpp
Range II / Resolution ..... 0 to 40 UIpp / 10 mUIpp
Range III / Resolution ..... 0 to 400 UIpp / 100 mUIpp
Measurement accuracy ..... as per O.172

Demodulator output
75 Ω, BNC socket
Range I (0 to 6.4 UIpp) ..... 0.25V / UIpp
Range II (0 to 80 UIpp) ..... 0.025V / UIpp
Range III (0 to 800 UIpp) ..... 0.0025V / UIpp

Wander Generator
Fully complies with or exceeds the requirements of ITU-T O.172

Bit rates
Wander generation at all implemented bit rates up to 622 Mbit/s according to the equipment level of the instrument.
Amplitude range ..... up to 200,000 UI
Frequency range .....10 µHz to 10 Hz
Accuracy ..... as per O.172
Resolution..... 1 µHz

Wander Analyzer
Fully complies with or exceeds the requirements of ITU-T O.172

Other sampling rates in addition to the 30/s rate are available for detailed analysis versus time:
Sampling rate – Low-pass filter –
Test duration ..... 1/s - 0.1 Hz - 99 days
30/s - 10 Hz - 99 h
60/s - 20 Hz - 99 h
300/s - 100 Hz - 5000 s
Amplitude range ..... ±1 ns to $\pm 10^6$ s
Measurement accuracy ..... as per O.172

Reference signal input
Frequencies ..... 1.544; 2.048; 5; 10 MHz
Bit rates ..... 1.544; 2.048 Mbit/s

Balanced 110 Ω connector ..... Bantam
Clock input voltage
(sine or square wave) ..... 1.0 to 6.5 Vpp
HDB3/B8ZS input voltage ..... ±3 V ±10%

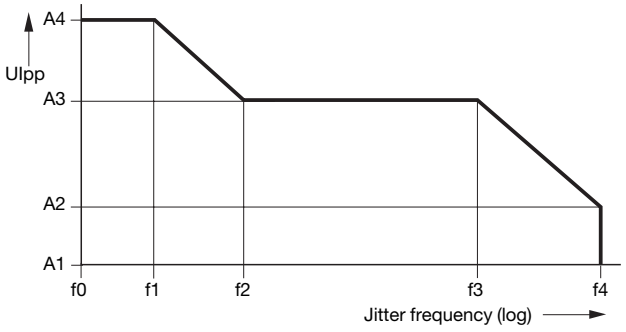
Coaxial 75 Ω connector ..... BNC
Clock input voltage
(sine or square wave) .....1.0 to 5 Vpp
HDB3/B8ZS input voltage .....±2.37 V ±10%

Accessory: "Standard Frequency Source" for wander applications, see end of chapter

O.172 Jitter/Wander up to 2488 Mbit/s — BN 3060/91.32

Jitter Generator
Fully complies with or exceeds the requirements of ITU-T O.172

Bit rate ..... 2,488,320 kbit/s
Generator signal ..... test patterns, frame structures depend on instrument configuration
Built-in modulation generator (sinewave)
or external ..... 0.1 Hz to 20 MHz
Jitter amplitude ..... up to 800 UIpp



Bit rate/ kHz	A1/ UIpp	A2/ UIpp	A3/ UIpp	A4/ UIpp	f0/ Hz	f1/ Hz	f2/ Hz	f3/ Hz	f4/ Hz
2488320 ANT-20SE	0.008	0.75	20	800	0.1	12.1	500	750 k	20 M

Modulator input
75 Ω, BNC socket
Modulation frequency ..... 0.1 Hz to 20 MHz
Required sinusoidal voltage ..... 0 to 2 Vpp

Error limits ..... to O.172

Jitter modulation of external signals in Through mode
In Through mode, jitter can be superimposed on an external 2488 Mbit/s signal in conjunction with the D&I option.
Internal and external modulation,
jitter amplitude ..... see jitter generator

Jitter Analyzer
Fully complies with or exceeds the requirements of ITU-T O.172

Bit rate ..... 2,488,320 kbit/s

Measuring ranges
Range I / Resolution..... 0 to 2 UIpp / 1 mUIpp
Range II / Resolution ..... 0 to 32 UIpp / 10 mUIpp
RMS Range I / Resolution ..... 0 to 1.0 UIpp / 1 mUIpp
RMS Range II / Resolution .....0 to 16 UIpp / 10 mUIpp

Built-in filters
as per ITU-T O.172, G.825, G.813, Bellcore GR-253, ANSI T1.105.03
High-pass filters ..... 5 kHz, 12 kHz, 1 MHz
Low-pass filter ..... 20 MHz
The high-pass filters can be switched off.
Frequency range without high-pass filter
Meas. range I ..... 80 Hz
Meas. range II ..... 10 Hz

Measuring modes . . . . . see Jitter Analysis

Demodulator outpur
75 Ω, BNC socket
Output voltage
Meas. range I (0 to 2 UIpp) . . . . . 1 V/ UIpp
Meas. range II (0 to 32 Uipp) . . . . . 62.5 mV/UIpp

Automatic tests . . . . . like jitter meter up to 622 Mbit/s
Tolerance masks at
MTJ / F-MTJ. . . . . G.825 (ANSI T1.105.03 and BELLCORE GR-253)
JTF . . . . . G.958, BELLCORE GR-253 and ANSI T1.105.03 TYPE A

Wander Generator
Fully complies with or exceeds the requirements of ITU-T O.172
Amplitude range. . . . . up to 200000 UI
Frequency range . . . . . 10 µHz to 10 Hz
Accuracy . . . . . as per O.172
Resolution . . . . . 1 µHz

Wander Analyzer
Other sampling rates in addition to the 30/s rate are available for detailed analysis versus time:
Sampling rate – Low-pass filter –
Test duration . . . . . 1/s - 0.1 Hz - 99 days
30/s - 10 Hz - 99 h
60/s - 20 Hz - 99 h
300/s - 100 Hz - 5000 s
Amplitude range . . . . . ± 1 ns to $\pm 10^6$ s
Measurement accuracy . . . . . as per O.172

Evaluation capabilities
see Wander Analysis

Reference signal input
75 Ω, BNC socket
Frequencies . . . . . 1.544; 2.048; 5; 10 MHz
Input voltage . . . . . 0.5 to 5 Vpp
Input signal monitoring
(Loss of Timing Input). . . . . .LTI

Accessory: “Standard Frequency Source” for wander applications, see end of chapter

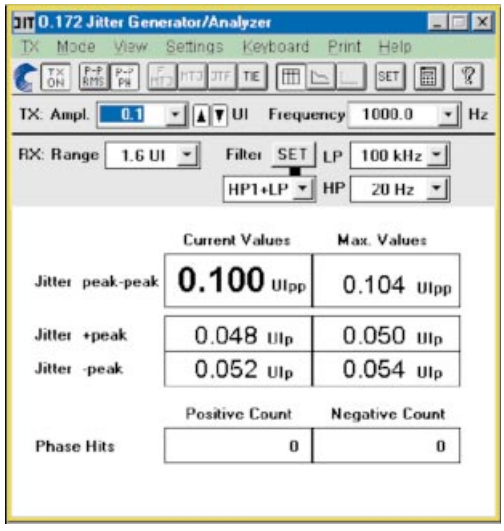
Jitter Analysis

Current values (continuous measurement)
Peak jitter value . . . . . .in UI_{pp}
Positive peak value . . . . . in UI_{+p}
Negative peak value. . . . . in UI_{-p}

Maximum value (gated measurement)
Maximum peak jitter value . . . . . in UI_{pp}
Maximum positive peak value . . . . . in UI_{+p}
Maximum negative peak value . . . . . in UI_{-p}

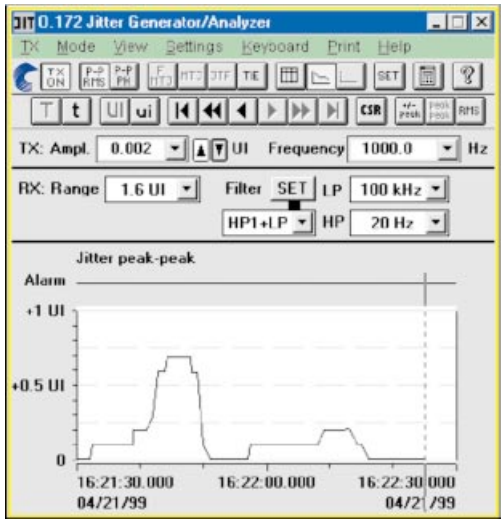
Result averaging (switchable) . . . . . 1 to 5 s

The ANT-20SE retains phase synchronicity even when pointer jitter occurs (phase tolerance to O.172).



Phase hits
The instrument detects when the programmable threshold for positive and negative jitter values is exceeded.
The result indicates how often this threshold was exceeded.
Setting range for positive and negative thresholds (depending on measurement range) . . . . . 0.1 up to the half measurement range

Jitter versus time
This function is used to record variations of jitter with time.
It allows the positive and negative peak values or peak-to-peak values to be displayed versus time.



Measured values have one second resolution. Measurement duration is up to 99 days.
By simultaneously evaluating alarms and errors, corellations between events can be quickly identified.

Clock jitter measurement
The ANT-20SE can also measure the jitter on the clock signals (square-wave) at standard bit rates. All built-in bit rates with electrical interfaces up to 155 Mbit/s can be measured.

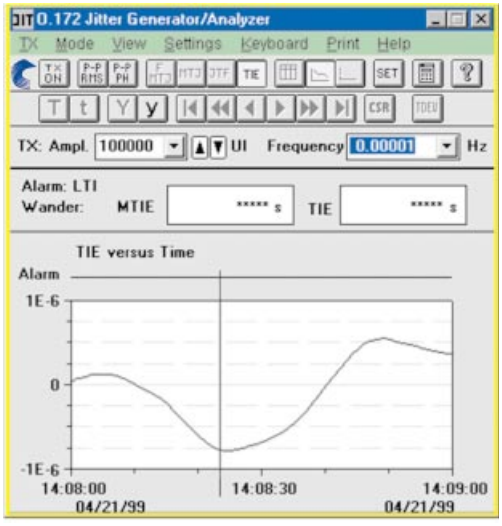
Specifications ANT-20SE – SDH version

RMS measurement
G.958 (or G.783 rev.), T1.105.03, GR-253, GR-499
The RMS value is measured on-line and displayed in UI.
The peak jitter and RMS values can be displayed simultaneously; a graph versus time is available for long-term analysis.
An RMS filter preset is available.

Wander Analysis

Time Interval Error (TIE)
to O.172 . . . . . numerical and graphical
Sampling rates . . . . . see under O.172 Wander Analyzer for up to 622 Mbit/s

MTIE is additionally determined as a continually updated numerical value.



To prevent data loss or premature termination of long term measurements, the ANT-20SE checks the remaining space on the hard disk before the start of the measurement. If necessary, the selected measurement time can be adjusted.
The TIE values are recorded and are then available for subsequent off-line MTIE/TDEV evaluations. The values are also saved in .csv format for documentation or further analysis.

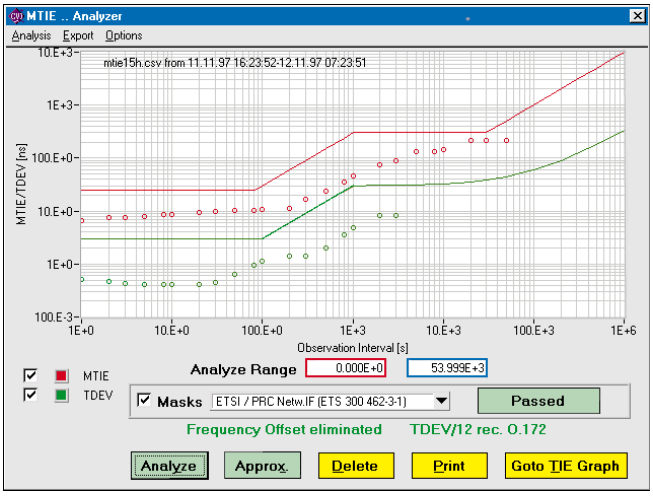
MTIE/TDEV Off-line Analysis Evaluation Software

This software provides extended off-line statistical analysis facilities for the results of wander measurements.

TIE values results obtained using the ANT-20SE are analyzed according to ETSI ETS 300 462, EN 302 084, ITU-T O.172, G.810 to G.813, ANSI T1.101, Bellcore GR-1244.

Network synchronization quality is presented graphically using the MTIE (maximum time interval error) and TDEV (time deviation) parameters. To ensure correct assessment, the tolerance masks for PRC (primary reference clock), SSU (synchronization supply unit), SEC (synchronous equipment clock) or PDH can be superimposed.

The results and masks can be printed out with additional user-defined comments.



This option allows several TIE results to be displayed simultaneously.

Decisive details during long term measurements disappear in the multitude of results. An effective zoom function is available for detailed wander characteristic analysis.

Result printout and export
The results can be printed out and stored internally or on floppy disk. The file format allows further processing using standard PC software.

Frequency offset and frequency drift rate (ANSI T1.101)
To ensure reliable operation when a clock source is in holdover mode, the frequency characteristics must not exceed specific deviation limits relative to an absolute reference source.
To verify this data, the ANT-20SE determines the following over the selected measurement interval:
Frequency offset . . . . . in ppm
Frequency drift rate . . . . . in ppm/s

MRTIE – Relative MTIE (G.823 and EN 302 084)
If the reference is unavailable (too far away) when analyzing the wander of asynchronous signals, the MTIE analysis may have a superimposed frequency offset.
This offset depends on the difference between the signal and local reference clocks.
The MRTIE measurement subtracts the frequency offset from the result so that the "actual" wander characteristic is shown.

Accessory for wander analysis
Standard frequency source . . . . . see end of chapter

Automatic Measurements

The following automatic measurements can be run for all standard bit rates and interfaces included in the mainframe configuration (electrical/optical) up to 2488 Mbit/s.

Automatic determination of selective jitter transfer function, JTF
ITU-T G.958, Bellcore GR-499, GR-253, ANSI T1.105.03

The jitter transfer function indicates the ratio of the jitter amplitude at the output of the device under test to that at the input at various frequencies.

This determines whether the device under test reduces or amplifies input jitter and at which frequencies. After a calibration measurement to minimize intrinsic errors, the ANT-20SE outputs a pre-selected jitter amplitude at various frequencies and measures selectively the jitter amplitude at the output of the device under test.
The ratio of the amplitudes in dB is the jitter transfer function.

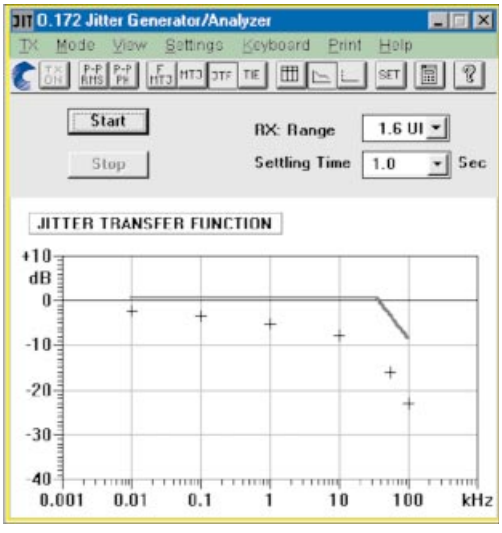
The preselected amplitudes correspond to the mask for maximum permitted input jitter. The jitter frequencies and amplitudes can also be edited. The calibration values can be saved and used again for other measurements.

Additional measurement mode
– Transfer MTJ results:
  An MTJ measurement is first performed. The measured amplitude values can then be used automatically as generator values for the JTF measurement.

The results can be displayed in tabular and graphical form.
The graphical display includes the standard tolerance masks specified in G.735 to G.739, G.751, G.758 or T1.105.03 and GR-253. The distance of the measurement points from the tolerance masks indicates the degree to which the device under test meets the requirements of the standard.

Tolerance mask violations during the measurement are indicated in the numerical table.

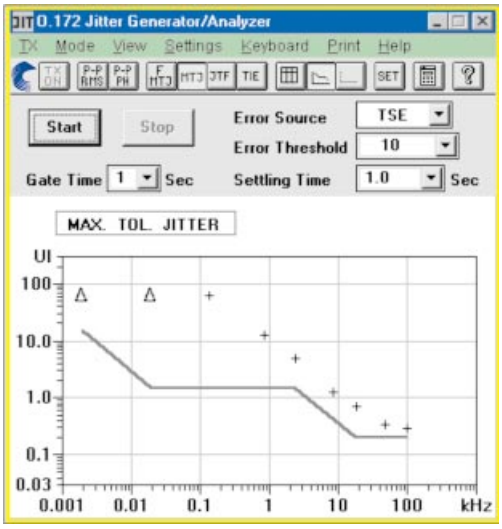
Freely programmable tolerance masks
The existing tolerance masks for the ANT-20SE can be altered as required to suit requirements that do not conform to specific standards. The new values selected for jitter frequency and jitter gain/loss are stored when the application is saved.



Automatic limit testing of maximum tolerable jitter (Fast Maximum Tolerable Jitter F-MTJ)
ITU-T G.823, G.824, G.825, G.958, ANSI T1.403, T1.404, T1.105.03, Bellcore GR-253, GR-499

This extremely fast measurement tests the device under test for conformance to the standard tolerance mask limits for maximum tolerable jitter.

Jitter frequencies . . . . . up to 10 fixed frequencies corresponding to standard tolerance mask



Detection criteria . . . . . TSE (bit error), code error, B2, B3, REI, RDI
Error threshold . . . . . 0 to 999999 errors
Settling time . . . . . 0.1 to 99.9 s

The editable frequency/amplitude values are set sequentially and the test pattern monitored for the permitted bit error count by the receiver.
The result of each measurement is shown in a table as the status message “OK” or “FAILED”.

Automatic determination of maximum tolerable jitter, MTJ
ITU-T G.823, G.824, G.825, G.958, ANSI T1.403, T1.404, T1.105.03, Bellcore GR-253, GR-499

The ANT-20SE automatically determines the maximum jitter amplitude tolerated by the device under test at each jitter frequency.
Jitter frequencies . . . . . 20 freely selectable frequencies
Detection criteria . . . . . TSE (bit error), code error, B2, B3, REI, RDI
Error threshold . . . . . 0 to 999999 errors
Settling time . . . . . 0.1 to 99.9 s
Gating time . . . . . 1 to 999 s

The maximum permissible jitter amplitude is determined precisely and quickly using a successive method.
The ANT-20SE determines the exact limit value.
The method is derived from long experience in the performance of jitter tolerance tests and is recognized by leading systems manufacturers.

The frequency/amplitude result pairs can be displayed in tabular and graphical form.

The graphical display includes the standard tolerance masks. The distance of the measurement points from the tolerance masks indicates the degree to which the device under test meets the requirements of the standard.

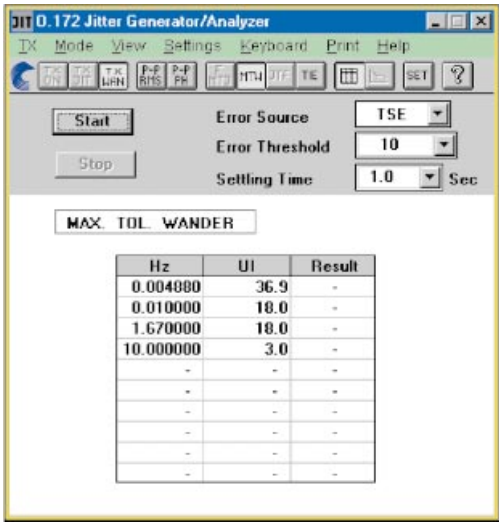
Tolerance mask violations during the measurement are indicated in the numerical table.

Freely programmable tolerance masks
The existing tolerance masks for the ANT-20SE can be altered as required to suit requirements that do not conform to specific standards. The new values selected for jitter frequency and amplitude are stored when the application is saved.

Specifications ANT-20SE – SDH version

Automatic pointer sequences for analyzing combined jitter
(available with CATS Test Sequencer option)
Among other things, ITU-T G.783 defines various pointer sequence scenarios for testing combined jitter (mapping and pointer jitter) at network elements.
These sequences are normally selected manually and the jitter measured. ANT-20SE allows simple automation of these sequences. The entire sequence is started and the maximum pointer jitter determined with a single key press. This saves considerable time spent in setting up the test and executing the measurement.

Automatic limit testing of maximum tolerable wander MTW
ITU-T G.823, G.824



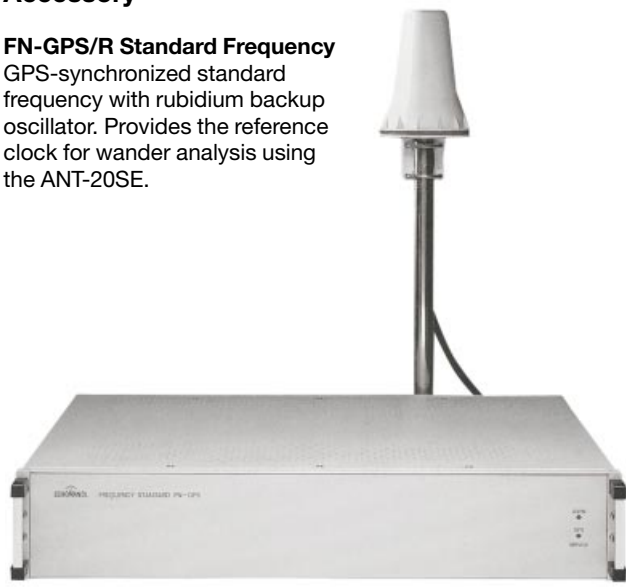
The ANT-20SE tests the device under test for conformance to the standard tolerance mask limits for maximum tolerable wander.

Measurement poinits . . . . . up to 10 Frequency/Amplitude values
Detection criteria . . . . . TSE (bit error), alarms
Frequency range . . . . . 10 Hz to 10 Hz, step 1 Hz
Amplitude range. . . . . 0.1 to 200 000 UI, step: 0.1 UI

The result of each measurement is shown in a table with an “OK” or “FAILED” message.

Accessory

FN-GPS/R Standard Frequency
GPS-synchronized standard frequency with rubidium backup oscillator. Provides the reference clock for wander analysis using the ANT-20SE.



Standard frequencies . . . . . 10 MHz, 2.048 MHz or others
Accuracy class . . . . . 10^{-11}

- Synchronizes to the GPS cesium reference oscillator
- Can be used anywhere in the world
- Precision rubidium backup oscillator
- Displays geographical position, date and time
- Display of control data and alarms
- Remote monitoring via modem link

A Schomandl company product, marketed by Wavetek Wandel Goltermann for wander applications.

ATM options

ATM Basic **BN 3060/90.50**

General

Adjustable test channel from 0 to 150 Mbit/s
In ATM network elements, user channels are monitored with the UPC (usage parameter control). The sensors of the control instance can be quickly checked if the bandwidth of a test channel exceeds the set threshold in the network element. For all measurements, the test channel in the ANT-20SE is set on-line. Settings are made directly with a control (figure 2) which shows the bandwidth in Mbit/s, Cells/s or %. This makes it easy to simulate CBR (constant bit rate) sources.
For each interface, the load setting has a range from 0.01 % to 100 %. This corresponds to the load conditions which can occur in the real world.

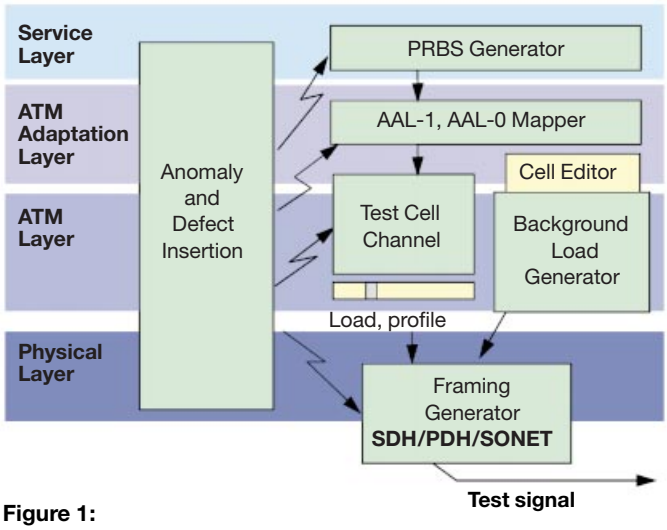


Figure 1:
ATM-BERT generator configuration

Load profiles
A test channel can be generated with typical load profiles in order to stress network elements or simulate source profiles. In burst mode, for example, the burst load, burst length and burst period parameters can be used to simulate a video signal whose key figures correspond to a real-life signal.

Background load generator
To make a real-time measurement under loaded conditions, additional background load can be simulated to supplement the test channel (foreground traffic). The ATM channels are defined using an editor. The user specifies the repetition rate of the load cell and a sequence of empty cells. Load channels can be transmitted continuously as a sequence. The load generator can also be used separately with the test channel switched off. In this case, the channels and profiles can be user-specified.

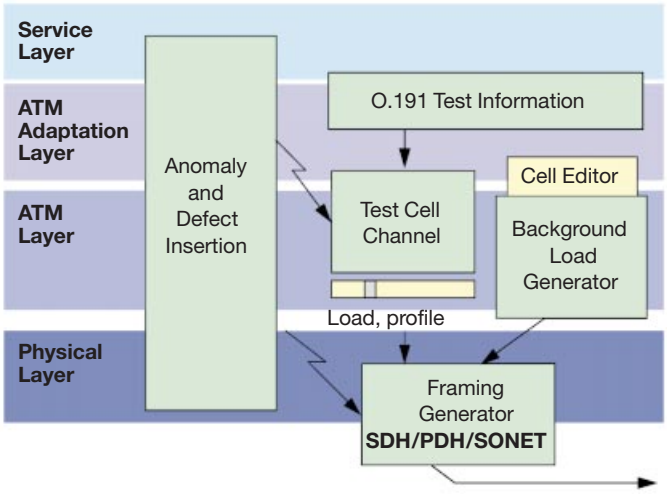


Figure 2: Generator configuration for performance measurement

Determining Cell Delay Variation
The ANT-20SE includes very powerful tools for measuring delay parameters. Once a precise measurement has been made, subsequent measurements usually require only a low-resolution display to allow rapid pass / fail assessment. Delay values are displayed by the ATM Traffic Analyzer as a histogram with a minimum class width equal to 160 ns (maximum 335 ms).
As a result, delay fluctuations are shown graphically with the same resolution. An adjustable offset can be used to maintain measurement accuracy even if the delay values are high, e.g. over international links.

F4/F5 OAM alarm flow
In accordance with I.610 and the ATM forum standard, the status of ATM paths and channels is transmitted in the OAM cell stream (fault management). The ANT-20SE generates the alarms VP-AIS, VC-AIS or VP-RDI, VC-RDI for the foreground channel. The receiver simultaneously detects alarms and error messages in the channel and path.

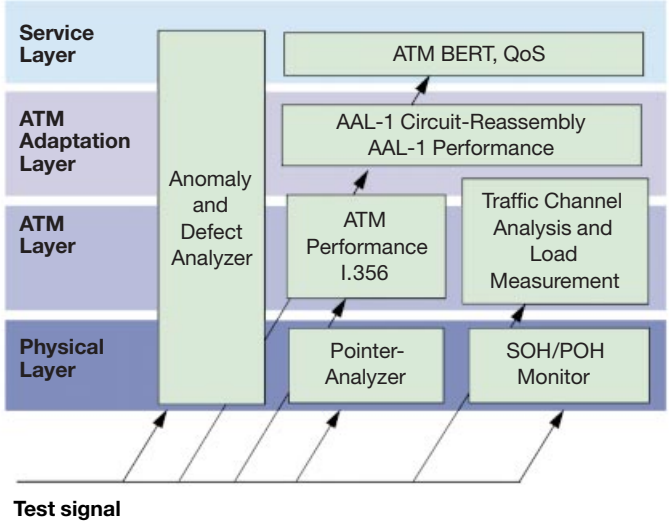


Figure 3: Analyzers in the ANT-20 – A hierarchical overview

Specifications ANT-20SE – SDH version

The ATM module comprises:
- Generation and analysis of ATM cell streams
- ATM layer cell transfer performance as per ITU-T I.356, O.191
- AAL-1 segmentation/reassembly for circuit emulation
- STM-1/STS-3c with C4 ATM mapping, ITU-T G.707, ANSI T1.105/107
- F4/F5 fault management OAM flow for AIS and RDI as per ITU-T I.610, ATM forum UNI 3.1

Generator unit

Bit rates of the framed cell streams . . . . . 155.520 Mbit/s
Cell scrambler $X^{43}+1$ (ITU-T) . . . . . can be switched on and off

Test cell channel
Adjustable from . . . . . 0 to 149.760 Mbit/s
Header setting . . . . . editor
Load setting in . . . . . Mbit/s, Cells/sec, %

Test cells, payload pattern
AAL-0, pseudo-random
bit sequences (PRBS) . . . . . 2^{11}–1, 2^{15}–1, 2^{23}–1
AAL-1, pseudo-random
bit sequences (PRBS) . . . . . 2^{11}–1, 2^{15}–1, 2^{23}–1
Programmable word, length . . . . . 16 bits
Test pattern for ATM performance analysis, with
Sequence number . . . . . 3 bytes
Time stamp . . . . . 4 bytes
Error correction CRC-16

Load profiles
Equidistant, setting range . . . . . 1 to 10000 cell times
CBR
Constant bit rate, setting range . . . . . 0.01% to 100 %
VBR
Variable bit rate, settings
Peak cell rate . . . . . 1% to 100 %
Mean cell rate . . . . . 1% to 100 %
Burst size . . . . . 1 to 1023 cell times
Burst period . . . . . 2 to 32767 cell times

Error insertion
Physical layer as with ANT-20SE basic instrument
ATM layer, AAL:
Correctable and non-correctable header errors
AAL-0, cell payload bit errors
AAL-1, sequence number errors
AAL-1, SAR-PDU bit errors
AAL-1 SNP, CRC errors
AAL-1 SNP, parity errors
Triggering . . . . . single errors, error ratio, N errors in M cells

Alarm generation
Physical layer as with basic instrument, also:
Loss of cell delineation . . . . . LCD
ATM layer (for selected test cell channel):
OAM F4/F5 fault flow . . . . . VP AIS, VP RDI, VP AIS+VC AIS, VC AIS, VC RDI, VP RDI+VC RDI

Background load generator
For programming user-defined cell sequences. The sequences can be transmitted at a selectable repetition rate.
Editor . . . . . 200 ATM channels
Header . . . . . user-selectable
Payload . . . . . 1 filler byte, user-selectable

Circuit emulation
(for selected test cell channel)
Generation of
an asynchronous channel . . . . . 1544, 2048, 6312, 8448, 34368, 44736 kbit/s, 2048 kbit/s with PCM30 frame structure
ATM channel segmentation . . . . . AAL-1, ITU-T I.363

Receiver unit

Bit rates of framed cell streams . . . . . 155.520 Mbit/s
Cell scrambler $X^{43}+1$ (ITU-T) . . . . . can be switched on and off

Measurement types

Error measurement (anomalies), statistics
Detection of the following error types:
Correctable and non-correctable header errors
AAL-0, cell payload bit errors
AAL-1, sequence number errors
AAL-1, SAR-PDU bit errors
AAL-1 SNP, CRC errors
AAL-1 SNP, parity errors

ATM performance analysis
- Cell error ratio
- Cell loss ratio
- Cell misinsertion rate
- Mean cell transfer delay
- 2-point cell delay variation
  measured between minimum and maximum cell transfer delay values
- Cell transfer delay histogram
  Number of classes 128
  Minimum class width . . . . . 160 ns
  Maximum class width . . . . . 335 ms
  Settable offset . . . . . 0 to 167 ms
  Offset step width . . . . . 2.5 µs

Alarm detection (defects)
Physical layer as with ANT-20SE basic instrument, also:
Loss of cell delineation . . . . . LCD
ATM layer (for selected test cell channel):
OAM F4/F5 fault flow . . . . . VP AIS, VP RDI, VC AIS, VC RDI

User channel analysis
Concurrent X-Y chart (load vs. time) for:
- All user cells
- Average cell rate of a selected cell channel
- Peak cell rate of a selected cell channel

Display units . . . . . Mbit/s, Cells/sec, %
Channel utilization histogram
- All user cells (“assigned cells”)
- A selected cell channel (“user cells”)

Cell distribution of a selected cell channel with classification by:
- User cells
- F5 OAM flow
- F4 OAM flow
- User cells with CLP = 1

Circuit reassembly
(for selected test cell channel)
Reassembly . . . . . AAL-1, ITU-T I.363
Error measurement on an
asynchronous channel . . . . . 1544, 2048, 6312, 8448, 34368, 44736 kbit/s, 2048 kbit/s with PCM30 frame structure

ATM Comprehensive **BN 3060/90.51**
includes the fuction of ATM BASIC BN 3060/90.50 and Broadband Analyzer Generator Module (BAG)

Selection of ready-to-run applications and graphics-supported test settings
The graphical method for making test settings is unique. The way that the ANT-20SE is connected to the device under test, the protocol layers and settings included in the test, or the ATM services to be tested can be quickly and easily seen. Users can select from a range of pre-defined test setups or customize their own. Pre-defined ATM channels can be selected from a data-base or new channels added. Additionally, all characteristics and parameters for each channel are also stored, for example: traffic type, circuit type, header, traffic contract, traffic source. An editor program is provided for defining the test circuits.

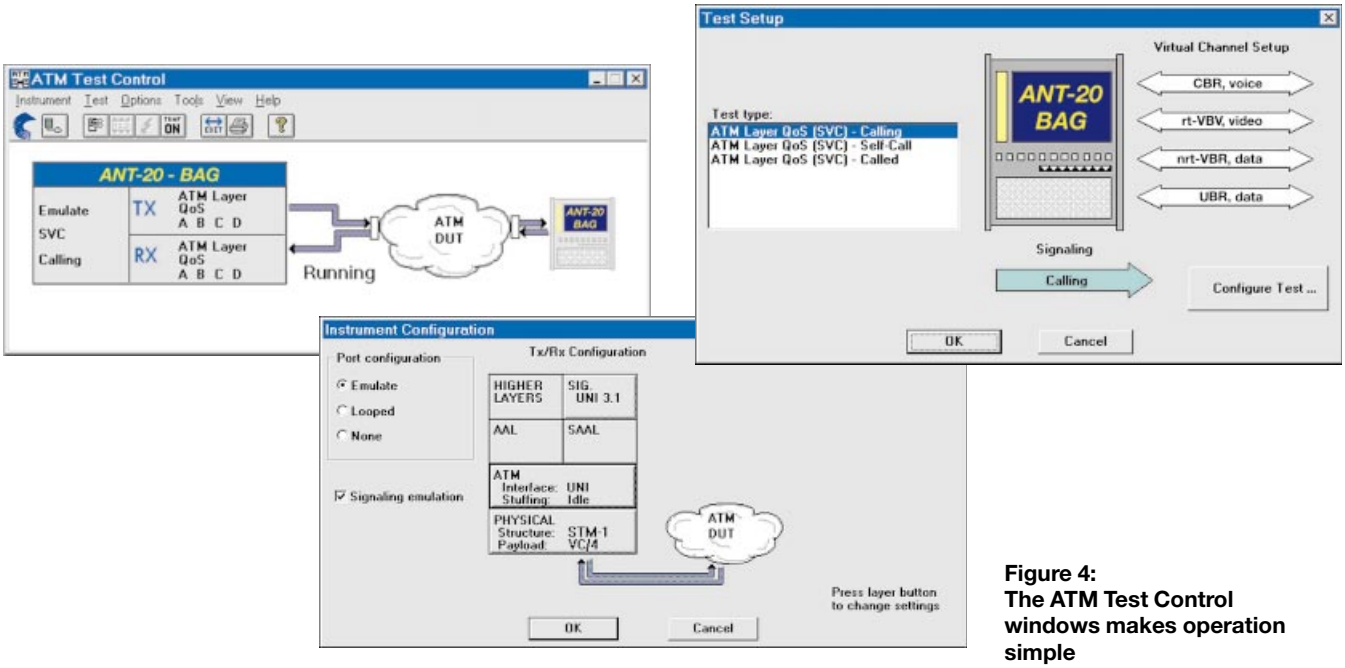


Figure 4:
The ATM Test Control windows makes operation simple

Direct testing of all contract parameters
Some of the main tasks facing measurement services are determining whether users are keeping to traffic contracts and how they are doing so, and establishing how the network handles such contracts. These questions can only be answered by means of a test that allows all the major service parameters to be set and measured.

For such applications, the Broadband Module includes an editor that permits all of the contract parameters for the various ATM services to be set for the first time.
For terminal emulation, all contract characteristics and of the traffic model used for the test can be defined with the Channel Editor.

After starting the measurement, the ANT-20SE generates test traffic using the selected parameters. This allows direct demonstration of the way that the ATM network handles the user traffic and whether the agreed network resources were in fact available.

The source parameters can be varied on-line during the measurement. This makes it possible to detect policing errors or incorrect network access threshold settings quickly and easily.

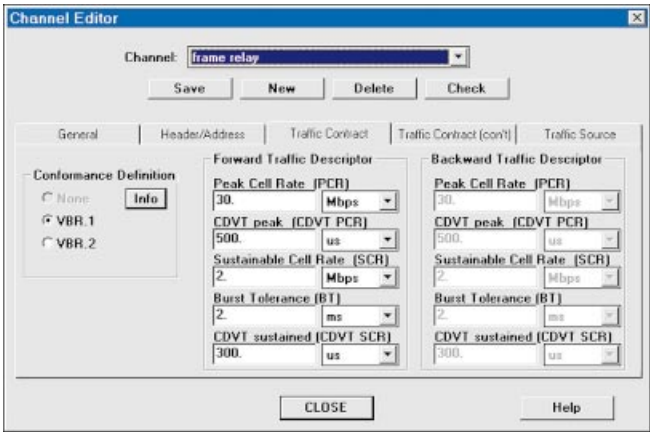


Figure 5: Channel Editor: Setting the traffic descriptor

Specifications ANT-20SE – SDH version

ATM QoS test with 4 different SVCs
The ANT-20SE with BAG can perform SVC and PVC tests on up to 4 circuits simultaneously. Multi-channel services, such as those used for multimedia applications, can thus be simulated. Any channel type can be selected from the database or newly defined for each channel.
Real-time measurements conform to the ITU-T O.191 standard which defines the test cell format and the test algorithm.
Important source parameters can be regulated on-line during the test.
The results are clearly displayed, with graphics elements used to indicate defects or highlight status information.

Signalling analysis
Sequence errors in the signalling protocol adversely affect correct management of ATM services. They can be detected by recording and displaying all channel states and changes of state in chronological order with timestamp information. The ANT-20SE constantly monitors the states of the SVCs being tested. The protocol can thus be checked for correctness and any errors detected rapidly. The connection set up time is measured for all test channels.

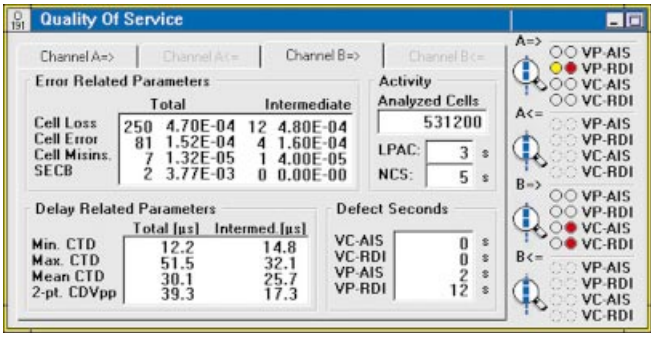


Figure 6: ATM test results for a real-time measurement on channel A

Traffic management and contract optimization
Traffic shaping (single/dual leaky bucket) can be switched on for each ATM channel, even on-line during the measurement. In addition, the following are displayed per channel with soft LEDs:
– Non Conforming Cells (NCC)
– Dropped Cells (DC)
Using this information it is possible to check whether the UPC (Usage Parameter Control) functions of the network are working and are implemented in compliance with the standard.
At the same time, the degree of utilization of the traffic contracts can be determined.
Using the facilities for simulating all relevant source parameters with up to four competing channels, it is possible to optimize the contract parameters in the network.

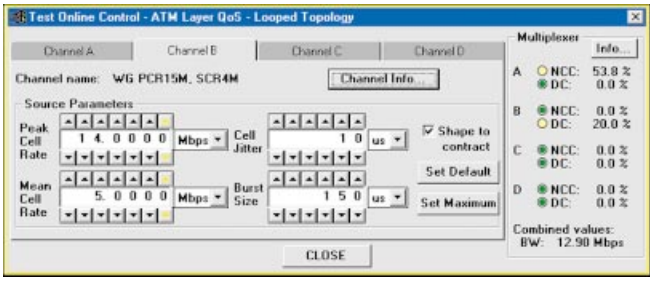


Figure 7: Soft-LED indication of multiplex results

Professional record of results
The ANT-20SE generates a professional record of instrument settings and test results that is output from a standard printer. The record can be used for various purposes, e.g.:
– Guarantee documentation
– Acceptance documentation
– Installation record
– Evidence of adherence to contract, etc.
In other words, the ANT-20SE handles the entire process from measurement through to producing a permanent record of the results.

Broadband Analyzer/Generator

The module includes software test functions for
– ATM Test Controller
– ATM Test Results
– ATM Channel Explorer
– STM-1/STS-3c with C4/SPE ATM mapping to ITU-T G.707, I.432 and ANSI T1.105/107

ATM test controller

Instrument port configurations
Emulation . . . . . SVCs, PVCs
Looped signal . . . . . PVCs

Test cell channels
4 test channels
settable from . . . . . 0 to 149.760 Mbit/s
Header setting . . . . . via editor
Load setting in . . . . . kbit/s, Mbit/s, cells/s
Test cell format . . . . . to ITU-T O.191

ATM service categories
Switched circuits and permanent circuits for:
Constant bit rate . . . . . CBR
Real-time variable bit rate . . . . . rt-VBR
Non real-time variable bit rate . . . . . nrt-VBR
Deterministic bit rate . . . . . DBR
Statistical bit rate . . . . . SBR
Unspecified bit rate . . . . . UBR

Signalling emulation
Terminal emulation at the UNI as per ITU-T and ATM Forum recommendations
Protocol types . . . . . UNI 3.0
UNI 3.1
Q.2931
Q.2961

Test types . . . . . Self-call, 2 SVCs
Calling, 4 SVCs
Called, 4 SVCs

ATM channel editor
Traffic contract:
Direction type . . . . . unidirectional
bi-directional symmetrical,
bi-directional asymmetrical
Traffic descriptor
Peak cell rate . . . . . PCR
Cell delay variation tolerance peak . . . . . CDVT peak
Sustainable cell rate . . . . . SCR
Burst tolerance . . . . . BT
Cell delay variation tolerance sustained . . . . . CDVT sustained
Source parameters . . . . . Cell clumping,
Burst size
Mean cell rate
Peak cell rate

On-line channel settings
Peak cell rate
Cell clumping
Mean cell rate
Burst size

Traffic management
User-selectable shaping
CBR . . . . . Single leaky bucket
DBR . . . . . Single leaky bucket
rt-VBR . . . . . Dual leaky bucket
nrt-VBR . . . . . Dual leaky bucket
SBR . . . . . Dual leaky bucket
UBR . . . . . Dual leaky bucket

Error insertion
Correctable and uncorrectable header errors
Cell loss
Cell error
Cell misinsertion
Severely errored cell blocks

Alarm generation
ATM layer alarms (for all test channels):
OAM F4/F5 fault flow . . . . . VP AIS, VP RDI, VC AIS, VC RDI

ATM test results

Measurement modes
ISM . . . . . In-service measurement
OOS . . . . . Out-of-service measurement

Receiver status (ISM, OOS)
Signal load, bandwidth
Correctable and uncorrectable header errors
Errored seconds . . . . . LCD, physical layer defects

ATM quality of service (OOS) for 4 SVCs or 4 PVCs
– Cell error ratio
– Cell loss ratio
– Cell misinsertion rate
– Mean cell transfer delay
– Maximum cell transfer delay
– Minimum cell transfer delay
– 2-point cell delay variation
– Severely errored cell block ratio

Errored seconds . . . . . VP AIS, VP RDI, VC AIS, VC RDI
Activity . . . . . Analyzed cells, Not connected seconds (SVCs),
Loss of performance assessments capability seconds

Alarm detection, defects (ISM, OOS)
ATM layer alarms (for selected test cell channel):
OAM F4/F5 fault flow . . . . . VP AIS, VP RDI, VC AIS, VC RDI

Signalling analysis
Channel set-up time
Channel status with interpretation and timestamp
Representation of ATM QoS for the SVC after clearing down the circuit.

ATM channel explorer (ISM, OOS)

Channel search:
Automatic determination of up to 1000 ATM channels with indication of:
Channel number . . . . . VPI, VCI
Explicit forward congestion
Indication bandwidth (%) . . . . . CI-BW
CLP = 1 bandwidth (%) CLP1-BW
Average bandwidth . . . . . AvBW
Current bandwidth . . . . . CuBW
Aging (switchable function)
Sorts out inactive channels from the activity list.

AAL analysis:
Automatic determination of AAL type for 1000 ATM channels.
Graphic display of distribution.

Trouble scan:
Automatic determination of VC AIS, VC RDI, VP AIS and VP RDI in up to 1000 ATM channels.

Add ATM SDH BN 3060/90.52

The ATM mapping options provide further frame structures for interfaces conforming to ITU-T G.804/832/707. Corresponding physical layer measurement functions are offered by the mapping options for the interfaces. These include error and alarm insertion, error measurement and alarm detection.

The following ATM mappings are included:
E4 (140 Mbit/s) ATM mapping
Bit rate . . . . . 139264 kbit/s

E3 (34 Mbit/s) ATM mapping
Bit rate . . . . . 34368 kbit/s

E1 (2 Mbit/s) ATM mapping
Bit rate . . . . . 2048 kbit/s

STM-1/VC3 ATM mapping
Bit rate . . . . . 155520 kbit/s

Add ATM SONET BN 3060/90.53

The ATM mapping options provide further frame structures for interfaces conforming to ANSI T1.105/107. Corresponding physical layer measurement functions are offered by the mapping options for the interfaces. These include error and alarm insertion, error measurement and alarm detection.

The following ATM mappings are included:
STS-1/STS-3 ATM mapping
Bit rate
STS-1 . . . . . 51840 kbit/s
STS-3 (3 x STS-1) . . . . . 155520 kbit/s

Specifications ANT-20SE – SDH version

DS3 (45 Mbit/s) ATM mapping
and STS-1 DS3 ATM mapping
PLCP-based mapping
HEC-based mapping
Bit rate . . . . . 44736 kbit/s

DS1 (1.5 Mbit/s) ATM mapping
Bit rate . . . . . 1544 kbit/s

OC-12c/STM-4c ATM testing BN 3060/90.91

Only in conjunction with BN 3060/90.50 and BN 3060/91.11 or BN 3035/91.12

Signal structure (TC sublayer) contiguous concatenation to T1.646, I.432 and af-phy-0046.000
Cell scrambler $X^{43}+1$ (ITU-T) . . . . . can be switched off

Test cell channel
Adjustable from . . . . . 0 to 149.760 Mbit/s
Header setting . . . . . editor
Load setting in . . . . . Mbit/s, Cells/sec, %

Test cells, pay load pattern
AAL-0, pseudorandom bit sequences
(PRBS) . . . . . 2^{11}–1, 2^{15}–1, 2^{23}–1
AAL-1, pseudorandom bit sequences
(PRBS) . . . . . 2^{11}–1, 2^{15}–1, 2^{23}–1
Programmable word, length . . . . . 16 bits
Test cells for ATM performance analysis:
Sequence number . . . . . 3 bytes
Timestamp . . . . . 4 bytes
Error checking CRC-16

Load profiles
Equidistant, setting range . . . . . 4 to 40000 cell times +1
CBR
Constant, setting range . . . . . 0.01% to 25%
VBR
Peak cell rate . . . . . 1% to 25%
Mean cell rate . . . . . 1% to 25%
Burst size . . . . . 4 to 4092 cell times
Burst period . . . . . 8 to 131068 cell times

Error insertion
Physical layer like basic ANT-20SE instrument
ATM layer, AAL:
Correctable and non-correctable header errors
AAL-0, cell payload bit error
AAL-1, sequence number error
AAL-1, SAR-PDU bit error
AAL-1 SNP, CRC error
AAL-1 SNP, parity error
Resolution:
Single error, error ratio, N errors in M cells
Al arm generat ion
Loss of cell delineation . . . . . LCD
ATM layer (for any selected cell channel):
OAM F4/F5 fault flow:
VP AIS, VP RDI, VP AIS+VC AIS
VC AIS, VC RDI, VP RDI+VC RDI
Background load generator
1 channel can be switched ON/OFF
Residual bandwidth . . . . . up to 599.040 Mbit/s
Header is freely definable

Circuit emulation
Generation of asynchronous channels:
1.544, 2.048, 6.312, 8.448, 34.368, 44.736 kbit/s,
2.048 kbit/s with PCM30 frame structure
ATM channel segmentation . . . . . AAL-1, ITU-T I.363

Error measurement, anomalies, statistics
Detection of following error types:
Correctable and non-correctable header errors
AAL-0, cell payload bit error
AAL-1, sequence number error
AAL-1, SAR-PDU bit error
AAL-1 SNP, CRC error
AAL-1 SNP, parity error

ATM performance analysis
– Cell error ratio
– Cell loss ratio
– Cell misinsertion rate
– Mean cell transfer delay
– 2-point cell delay variation
  Measured between greatest and smallest value of cell transfer delay
– Cell transfer delay histogram:
Number of classes 128
Min. class width . . . . . 160 ns
Max. class width . . . . . 335 ms
Adjustable offset . . . . . 0 to 167 ms
Offset steps . . . . . 2.5 µs

Alarm detection, defects (ISM, OOS)
Loss of cell delineation . . . . . LCD
ATM layer (for any selected cell channel):
OAM F4/F5 fault flow:
VP AIS, VP RDI, VC AIS, VC RDI

Traffic channel analysis
Time chart simultaneously for
– All traffic cells
– Average cell rate of any selected cell channel
– Peak cell rate of any selected cell channel
Display in . . . . . Mbit/s, Cells/sec, %

Channel utilization histogram
– All assigned cells
– One selected cell channel (user cells)

Cell distribution in traffic channel
Classification of one selected cell channel by
– User cells
– F5 OAM flow
– F4 OAM flow
– User cells with CLP = 1

Circuit reassembly
Reassembly . . . . . AAL-1, ITU-T I.363
Error measurement on asynchronous channels:
1.544, 2.048, 6.312, 8.448, 34.368, 44.736 kbit/s,
2.048 kbit/s with PCM30 frame structure

CATS – ANT-20SE applications in the remote controlled production environment

V.24 remote control **BN 3035/91.01**
Remote control of instrument functions using SCPI command structure

Interface . . . . . V.24 / RS232

GPIB (PCMCIA) remote control **BN 3035/92.10**
Remote control of instrument functions using SCPI command structure. A GPIB adapter card for the ANT-20SE PCMCIA interface is supplied with this option
Interface . . . . . GPIB

LabWindows drivers **BN 3038/95.99**
Simplifies creation of remote-control programs for automated testing using LabWindows.
The drivers can be used with options BN 3035/91.01 and BN 3035/92.10.

Test Sequencer (CATS) and Test Case Library BN 3035/95.90

The Test Sequencer is the ideal tool for rapid, simple adaptation and automatic performance of complete test sequences on the ANT-20SE (CATS = CVI Application Test Sequence). This saves time where repetitive tests are required in the production, installation and monitoring of SDH, SONET and ATM network elements. The comprehensive test case library includes solutions for various applications, such as BERTs, alarm sensor tests, jitter, offset and pointer tests and monitoring ATM quality of service (QoS) parameters. Once created, test sequences are started with a single mouse click. A report in ASCII format for documentation purposes is compiled during the measurement. All test cases are pre-defined and ready to run. They can also be easily customized. The Test Sequencer is part of the WG CATS range (figure 1).

More information is found in the CATS data sheet.

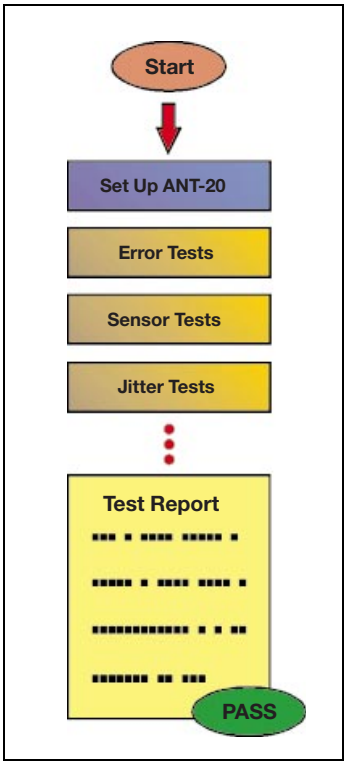


Figure 1: Automatic test sequences with the ANT-20SE

Remote ANT-20SE operation (figure 2)

These options allow operation of the ANT-20SE from a Windows PC. The complete ANT-20SE user interface is transferred to the PC screen via modem or LAN link. This means that all the functions of the instrument can be used from any remote location. The results are simply transferred to the controlling PC for further processing.
Applications include troubleshooting networks or centralized operation of test instrumentation and devices in the production and system test environment.

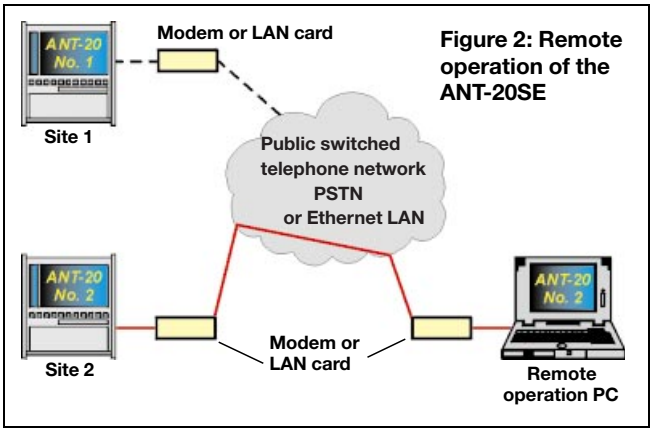
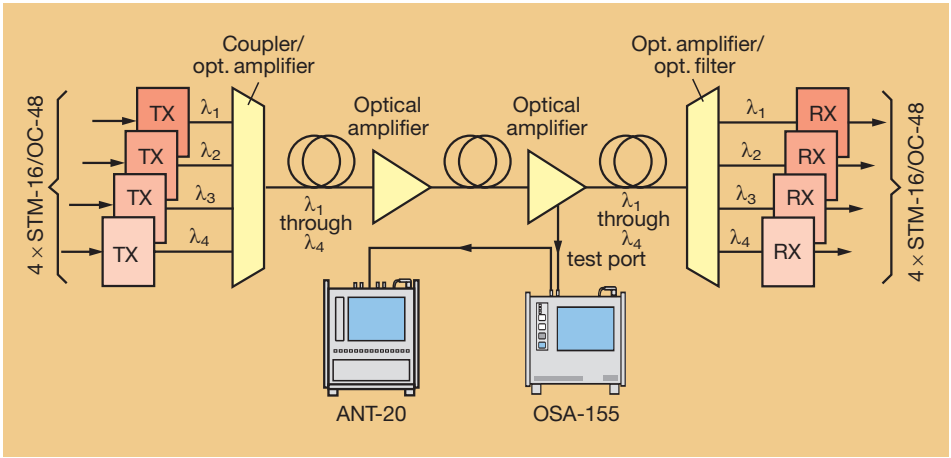


Figure 2: Remote operation of the ANT-20SE

Remote Operation via Modem **BN 3035/95.30**
Provides remote operation via a PCMCIA or external modem (V.24) which must be purchased separately.

Remote Operation via LAN (TCP/IP) **BN 3035/95.31**
Provides remote operation via a PCMCIA Ethernet card (included)

CATS DWDM – A complete solution for measurements on DWDM networks with ANT-20SE and OSA-155



Specifications ANT-20SE – SDH version

Together, the ANT-20SE and OSA-155 form a powerful tool for interactive or automatic testing of DWDM (Dense Wavelength Division Multiplex) systems.
The WG CATS Test "Optics" Testcase Library offers a number of test cases for measuring optical DWDM parameters (wavelength, level, S/N, tilt). These test cases may run directly on the ANT-20SE's built-in PC and control the connected OSA-155 via the GPIB bus or V.24 interface.
The OSA-155 routes a signal filtered out of the "color mixture" of a DWDM signal to a monitoring jack. This signal, e.g. STM-16 or OC-48, can be fed to the optical input of the ANT-20SE. Transmission measurements (e.g. error rates, alarm monitoring, jitter, pointers, wander) can thus be combined with optical parameter measurements, enabling complete characterization of the overall quality of a DWDM system. No external controller is required.
All of the measurements can be initiated from a remote site (modem or TCP/IP), and complete integration of this solution into network management systems is simple, as described above.

NEXT – Network Expert Test Software

ANT-20SE NEXT Network Expert Diagnostics System **BN 3035/95.40**
Complete software package for characterization of SDH/PDH lines for 2 Mbit/s and STM-1

Requirements:
Mux/Demux Chain option BN 3060/90.11
Extended SDH testing BN 3060/90.01

If jitter measurements and MTJ measurements are also required, the following are needed:
O.172 Jitter/Wander up to STM-1 BN 3060/91.30

Network operators must bring into service and maintain a growing number of lines, including leased lines and those used for corporate internal purposes. The only way to assure the quality and availabi-lity of delivered transmission capacity is through conscientious measurements, which are, quite simply, a job for experts.

Specifications CATS DWDM

Note:
The following only lists the system-specific data for the ANT-20/OSA-155 combination.
The specifications for the individual instruments should be taken from the corresponding instrument data sheets.

Level limits
Maximum insertion loss of OSA-155 . . . . . 7 dB
Minimum tributary input level to OSA-155 . . . . . –20 dBm
applies if ANT-20 is to be connected downstream

Bit rate limits
SDH/SONET measurements can be made at:
SDH . . . . . 622 Mbit/s (STM-4) or 2.5 Gbit/s (STM-16)
SONET . . . . . 622 Mbit/s (OC-12) or 2.5 Gbit/s (OC-48)

Software specifications
- All ANT-20SE test cases included in BN 3035/95.90 (see ANT-20SE data sheet).

Additional test cases with the OSA-155:
- DWDM system parameter settings (number of tributaries, nominal wavelengths)
- Measurement of tributary wavelengths, optical level and OSNR (optical signal to noise ratio)
- Setting of nominal wavelengths for output via the OSA-155 monitor output; each wavelength can be labeled with a plain text name.

Ordering information CATS DWDM

CATS DWDM Software **BN 3045/93.43**
Complete package including the full functions of the CATS ANT-20 Test Sequencer, BN 3035/95.90, and all test cases required for controlling the OSA-155. The software is to be installed on the ANT-20SE.

WG OSA-155 with monitor output **BN 2260/04**
For details, see data sheet for WG OSA-155
GPIB remote control (PCMCIA) BN 2260/90.03

ANT-20/ANT-20E/DominoCOM ANT-20 **BN 3035/xx**
For details, see data sheets for ANT-20, ANT-20E or DominoCOM ANT-20
GPIB remote control (PCMCIA) BN 3035/92.10

Zero modem cable **K 764**

Note:
We recommend use of the GPIB remote control option for the ANT-20SE and the OSA-155 for maximum flexibility and expandability.
The ANT-20SE can also be connected to the OSA-155 via a zero modem cable (connected to the V.24/RS 232 interface present as standard in both instruments) for purely local applications. Options BN 2260/90.03 and BN 3035/92.10 are not required in this case, but it is not possible to control test point scanners or other additional equipment with this configuration.

Ordering information ANT-20SE

ANT-20SE Advanced Network Tester, SDH version

(Includes STM-1 VC-12 mapping;
CPU RAM extension to 32MB;
menu in English or German.)
With color TFT display touch screen **BN 3060/01**

Options

Extended SDH testing BN 3060/90.01
C3 (34 Mbit/s in STM-1)
C4 (140 Mbit/s in STM-1)
C11 (1.5 Mbit/s in STM-1)
C3 (45 Mbit/s in STM-1)
C2 (6 Mbit/s in STM-1)
APS, TCM Analysis
OH capture, OH sequencing

Add SONET BN 3060/90.03
STM-0 mappings
STM-0 and VT2 SPE (2 Mbit/s)
STM-0 and VT1.5 SPE g (1.5 Mbit/s)
VT6 SPE (6 Mbit/s)
STM-0 and STS-1 SPE (34/45 Mbit/s)
BERT (1.5/6/45 Mbit/s)

Drop & Insert BN 3060/90.10

M13 MUX/DEMUX chain BN 3060/90.12

PDH 64k/140M MUX/DEMUX chain BN 3035/90.11

Optical interfaces
The following options BN 3060/91.01 to /91.12 are alternatives.
Optical OC-1/3, STM-0/1, 1310 nm BN 3060/91.01
Optical OC-1/3, STM-0/1, 1310 & 1550 nm BN 3060/91.02
Optical OC-1/3/12, STM-0/1/4, 1310 nm BN 3060/91.11
Optical OC-1/3/12, STM-0/1/4,
1310 & 1550 nm BN 3060/91.12
The options BN 3060/91.50 to /91.53 are alternatives.
Optical STM-16, OC-48, 1310 nm BN 3060/91.50
Optical STM-16, OC-48, 1550 nm BN 3060/91.51
Optical STM-16, OC-48,
1310/1550 nm switchable BN 3060/91.52
Optical STM-16, OC-48, 15xy nm BN 3060/91.53
Select a wavelength between 1530.33 nm
and 1560.61 nm to G.692.

OC-12c/STM-4c Options
OC-12c/STM-4c Bit Error Tester BN 3060/90.90
requires Optical Module BN 3060/91.11 or /91.12
OC-12c/STM-4c ATM Testing BN 3060/90.91
requires Optical Module BN 3060/91.11 or /91.12
and ATM BASIC BN 3060/90.50
OC-12c/STM-4c Virtual Concatenation BN 3060/90.92
requires BN 3060/90.90 or /90.91

OC-48c/STM-16c Option
OC-48c/STM-16c Bit Error Tester (Bulk) BN 3060/90.93

Optical Packages
include optical interfaces from 52 Mbit/s to 2488 Mbit/s and four optical adapters – please select; include STM-16c/OC-48c BULK, STM-4c/OC-12c BULK
Optics STM-0/1/4/16, OC-1/3/12/48, 1310 nm BN 3060/90.55
Optics STM-0/1/4/16, OC-1/3/12/48, 1550 nm BN 3060/90.56
Optics STM-0/1/4/16, OC-1/3/12/48,
1310 &1550 nm BN 3060/90.57
Optics STM-0/1/4, OC-1/3/12, 1310 nm
Optics STM-16, OC-48, 1550 nm BN 3060/90.58

Optical Attenuator (plug-in) BN 2060/00.61
SC-PC, 1310 nm, 15 dB

Optical power splitter (90/10%) BN 3060/91.05
includes 3 optical adapters – please select

Optical test adapters
ST type (AT&T) BN 2060/00.32
HMS-10/A, HFS-13/A (Diamond) BN 2060/00.34
HMS-10, HFS-13 (Diamond) BN 2060/00.35
“Keyed Biconic”, Twist-Proof (AT&T) BN 2060/00.37
D4 (NEC) BN 2060/00.40
DIN 47256 BN 2060/00.50
FC, FC-PC (NTT) BN 2060/00.51
E 2000 (Diamond) BN 2060/00.53
SC, SC-PC NTT (NTT) BN 2060/00.58

Wavetek Wandel Goltermann offers a wide range of optical power meters, sources and attenuators. Contact your local sales representative for details.

O.172 Jitter and wander
O.172 JitterWander Paket up to 155 Mbit/s BN 3060/91.30
Includes MTIE/TDEV offline analysis
O.172 Jitter/Wander Packet up to 622 Mbit/s BN 3060/91.31
Includes MTIE/TDEV offline analysis
O.172 Jitter/Wander Packet up to 2488 Mbit/s BN 3060/91.32
includes MTIE/TDEV offline analysis

ATM functions

ATM BASIC for STM-1/STS-3c BN 3060/90.50
ATM Comprehensive BN 3060/90.51
(includes ATM BASIC and BAG)

Add ATM SDH
(requires ATM module BN 3060/90.50 or BN 3060/90.51)
E4 (140 Mbit/s) ATM mapping
E3 (34 Mbit/s) ATM mapping
E1 (2 Mbit/s) ATM mapping
VC-3 ATM mapping in STM-1 (AU-3/AU-4) BN 3060/90.52

Add ATM SONET
(requires ATM module BN 3060/90.50 or BN 3060/90.51)
STS-1 (51 Mbit/s) ATM mapping
DS3 (45 Mbit/s) ATM mapping
DS1 (1.5 Mbit/s) ATM mapping BN 3060/90.53

OC-12c/STM-4c ATM Testing BN 3060/90.91
requires Optical Module BN 3060/91.11 or /91.12

Remote control
V.24 remote control BN 3035/91.01
GPIB remote control BN 3035/92.10
LabWindows CVI driver BN 3038/95.99

Remote operation
Remote operation via modem BN 3035/95.30
Remote operation via LAN (TCP/IP) BN 3035/95.31

Specifications ANT-20SE – SDH version

Test automation

CATS test sequencer and test case library	BN 3035/95.90

Calibration report BN 3060/94.01
(Calibration is carried outin accordance with quality management system crtified to ISO9001.)

ANT-20SE NEXT

Network Expert Test Software	BN 3035/95.40

Accessories

Transport case for ANT-20SE	BN 3035/92.03
External keyboard (UK/US)	BN 3035/92.04
Decoupler (–20 dB, 1.6/5.6 jack plug)	BN 3903/63
TKD-1 probe, 48 to 8500 kbit/s	BN 822/01
WG PenBERT mini PCM monitor (E1) (see WG PenBERT data sheet for details)	BN 4555/11

Training courses
Location: D-72800 Eningen u.A., Germany
Information about availability and other locations available on request.

“SDH/SONET troubleshooting”	BN 3035/89.01
“Synchronization”	BN 3035/89.02
“Solving Jitter Problems”	BN 3035/89.03
“SDH/SONET Quality of Service”	BN 3035/89.04
“Optimizing Your SDH/SONET Network”	BN 3035/89.05
“Turning up ATM Services”	BN 3035/89.30
“ATM Traffic Management”	BN 3035/89.31
“ATM Quality of Service”	BN 3035/89.32

ANT-20SE – combination and parallel operation of all bit rates up to STM-16 with jitter/wander up to 2.5 Gbit/s and ATM in a single unit. Now also with STM-64 optical interfaces.

ANT-10Gig is a subset of the ANT-20SE. This test solution handles OC-192/STM-64, taking you one step further into the future. It offers access to all standard interfaces from 1.5 Mbit/s up to 10 Gbit/s.

ANT-20 – Compact and handy for field work. It offers one extension slot for STM-16, Jitter up to STM-4 or Comprehensive ATM testing.

DominoCOM ANT-20 is the "black box" version of the ANT-20 and is ideal for use in automated test systems. Remote-control interfaces are fitted as standard and the unit can be rack mounted. Refer to the DominoCOM data sheet for more details.

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